

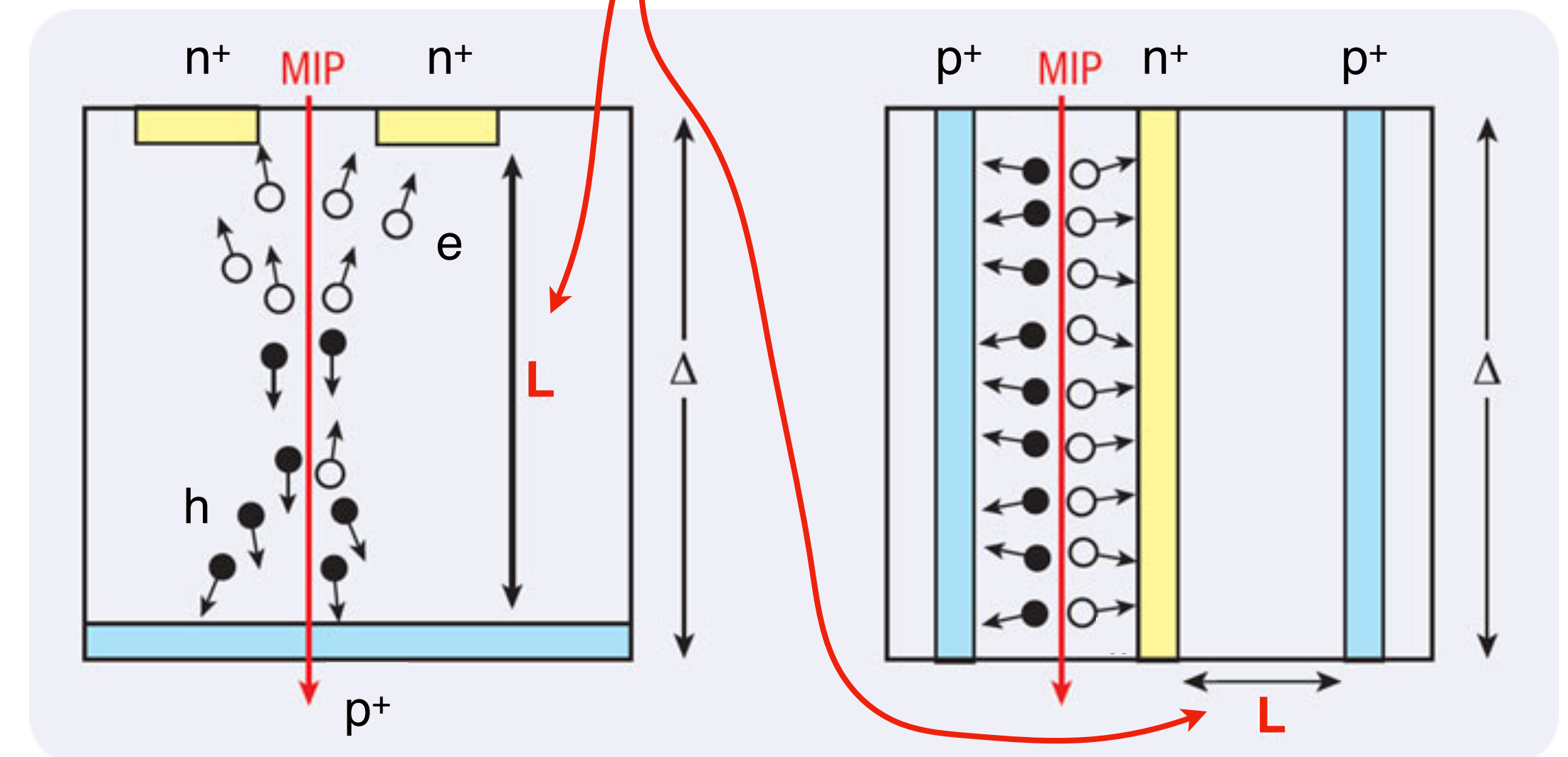
Characterisation of 3D pixel sensors for the CMS upgrade at the High Luminosity LHC

- The CMS Inner Tracker upgrade
- 3D sensor fabrication
- Readout chip and testbeam setup
- Results
- Summary

HL-LHC operation conditions	Sensor design constraints
Luminosity $7.5 \times 10^{34}/(\text{cm}^2 \cdot \text{s}) \rightarrow$ up to 200 events/25 ns bunch crossing	Maintain occupancy at ‰ level and increase spatial resolution \rightarrow pixel size $\times 6$ smaller than present pixels \rightarrow $25 \times 100 \mu\text{m}^2$ (current detector in CMS $100 \times 150 \mu\text{m}^2$)
CMS baseline choice: replace pixel layer closer to beamline at integrated fluence $\sim 1.9 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$ (end of “Run 5”, i.e. after ~ 6 years of operation) \rightarrow electron mean free path greatly reduced (also damaged readout ASIC at ~ 1 Grad)	Reduce electrodes distance (L) to increase electric field and thus the signal \rightarrow thin planar or 3D columnar technologies

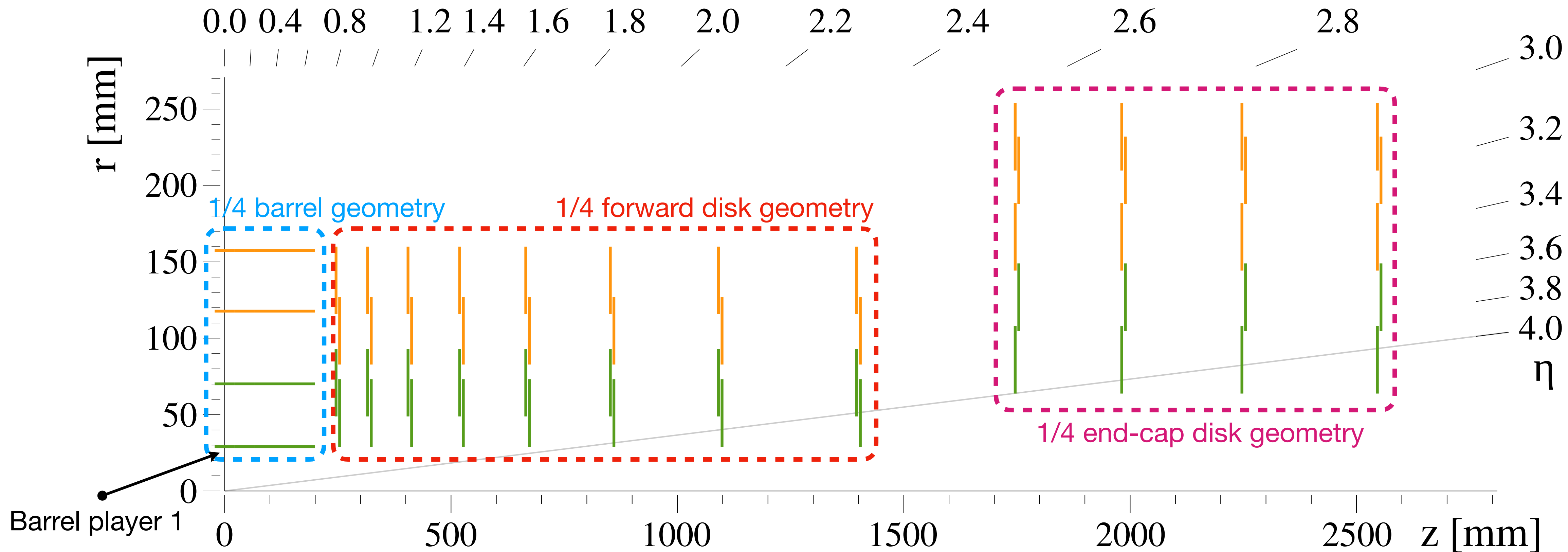
3D silicon sensors made by

- Fondazione Bruno Kessler-**FBK** (Trento, Italy), **n-in-p** sensors on **150 mm FZ wafers** in collaboration with **INFN**
- Centro Nacional Microtecnologia-**CNM** (Barcelona, Spain), **n-in-p** sensors on **100 mm FZ wafers**



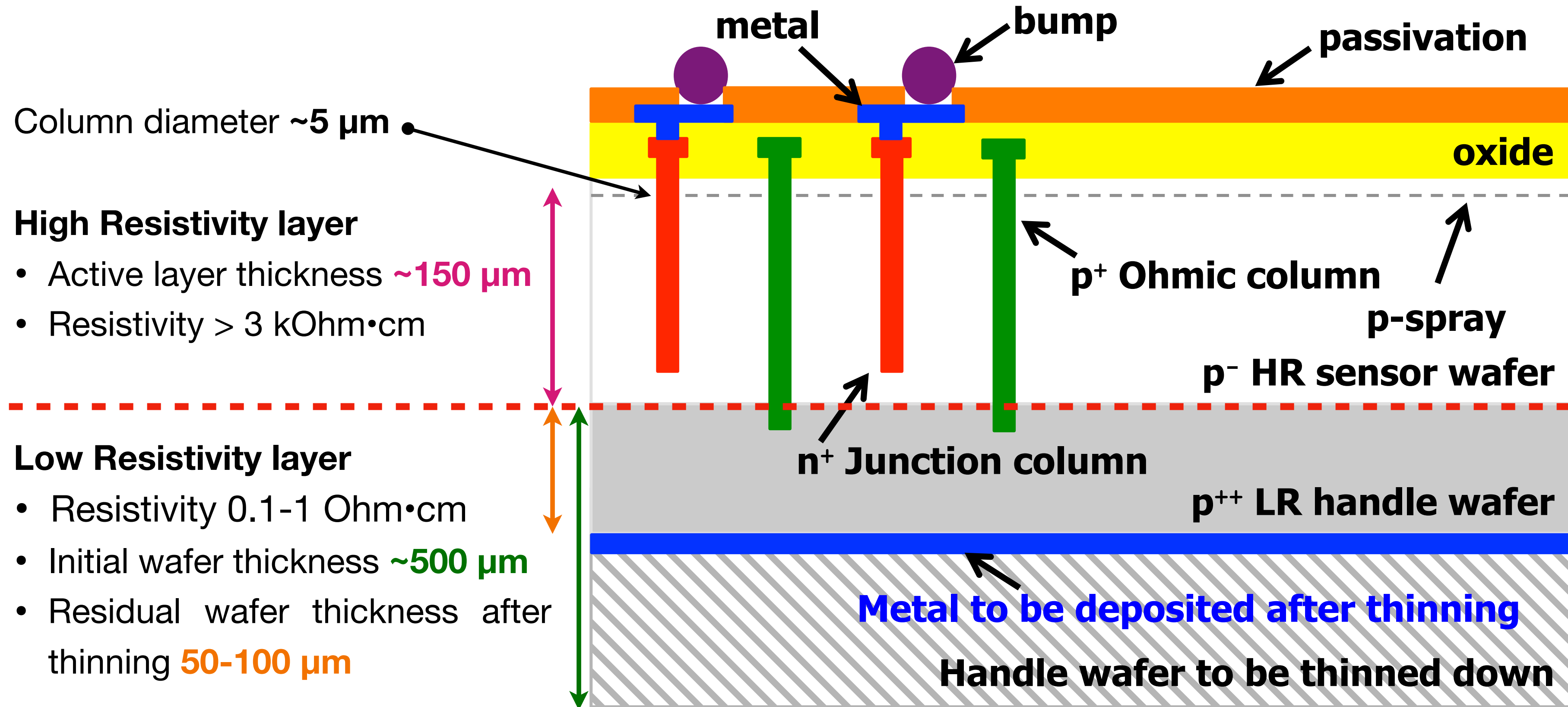
C. Da Vià et al., NIMA (2012)

The CMS Inner Tracker upgrade for the High Luminosity LHC



Sensor main features

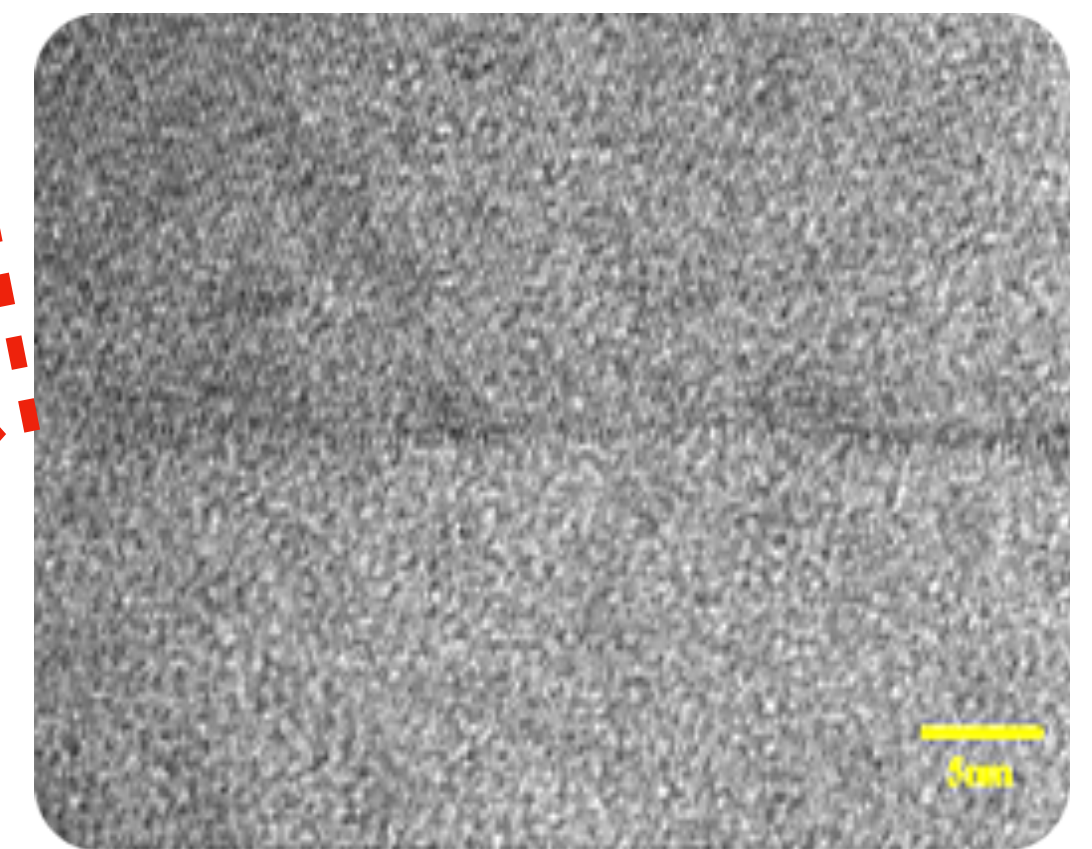
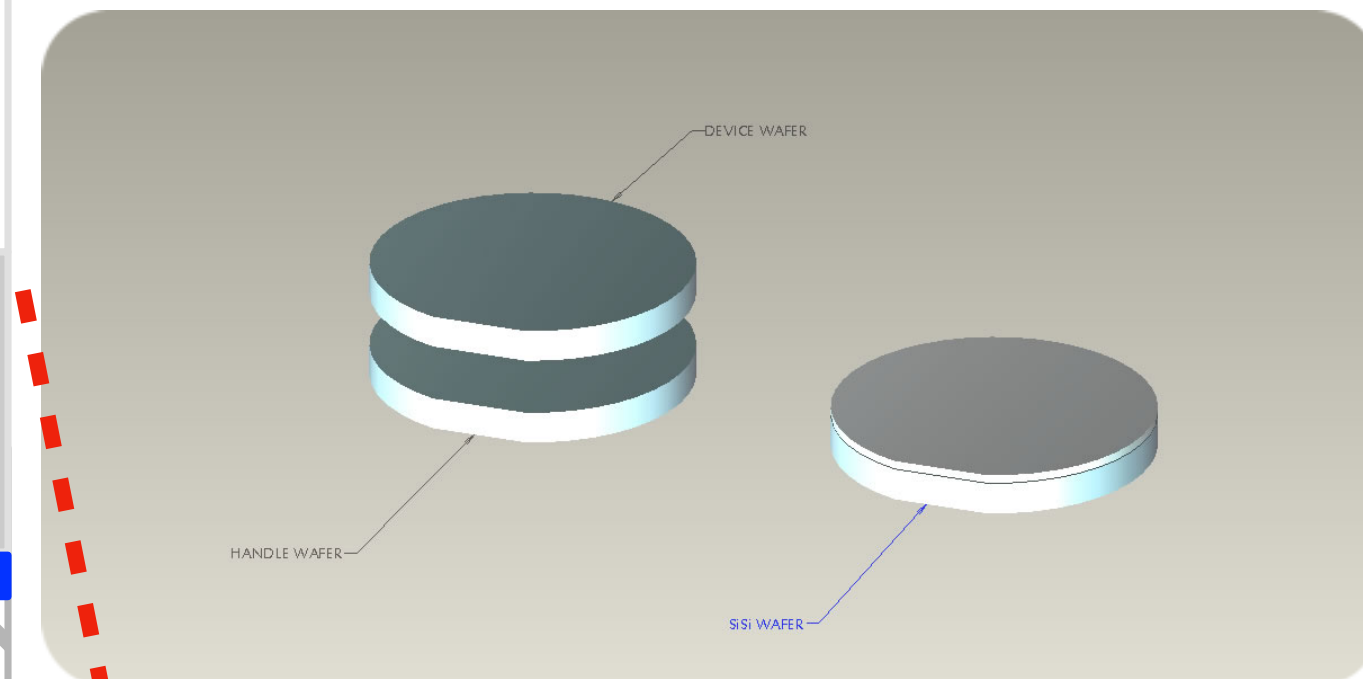
- **~2 billion pixels** → active surface $\sim 4.9 \text{ m}^2$ (**4 barrel** layers and **12+12 forward / end-cap** disks)
- **Planar $25 \times 100 \text{ } \mu\text{m}^2 \times 150 \text{ } \mu\text{m}$ active length** sensors baseline choice for whole Inner Tracker but barrel layer 1
- **3D** sensors, **same size** of planar, baseline choice for **barrel layer 1** (better thermal performance than planar)
- $50 \times 50 \text{ } \mu\text{m}^2 \times 150 \text{ } \mu\text{m}$ active length discarded since marginal gain doesn't justify additional design



G.F. Dalla Betta et al., NIMA 824 (2016) 386

Two wafers:

High-Resistivity and Low-Resistivity, bonded with **Direct Wafer Bond - DWB** technique by IceMos Technology, Belfast

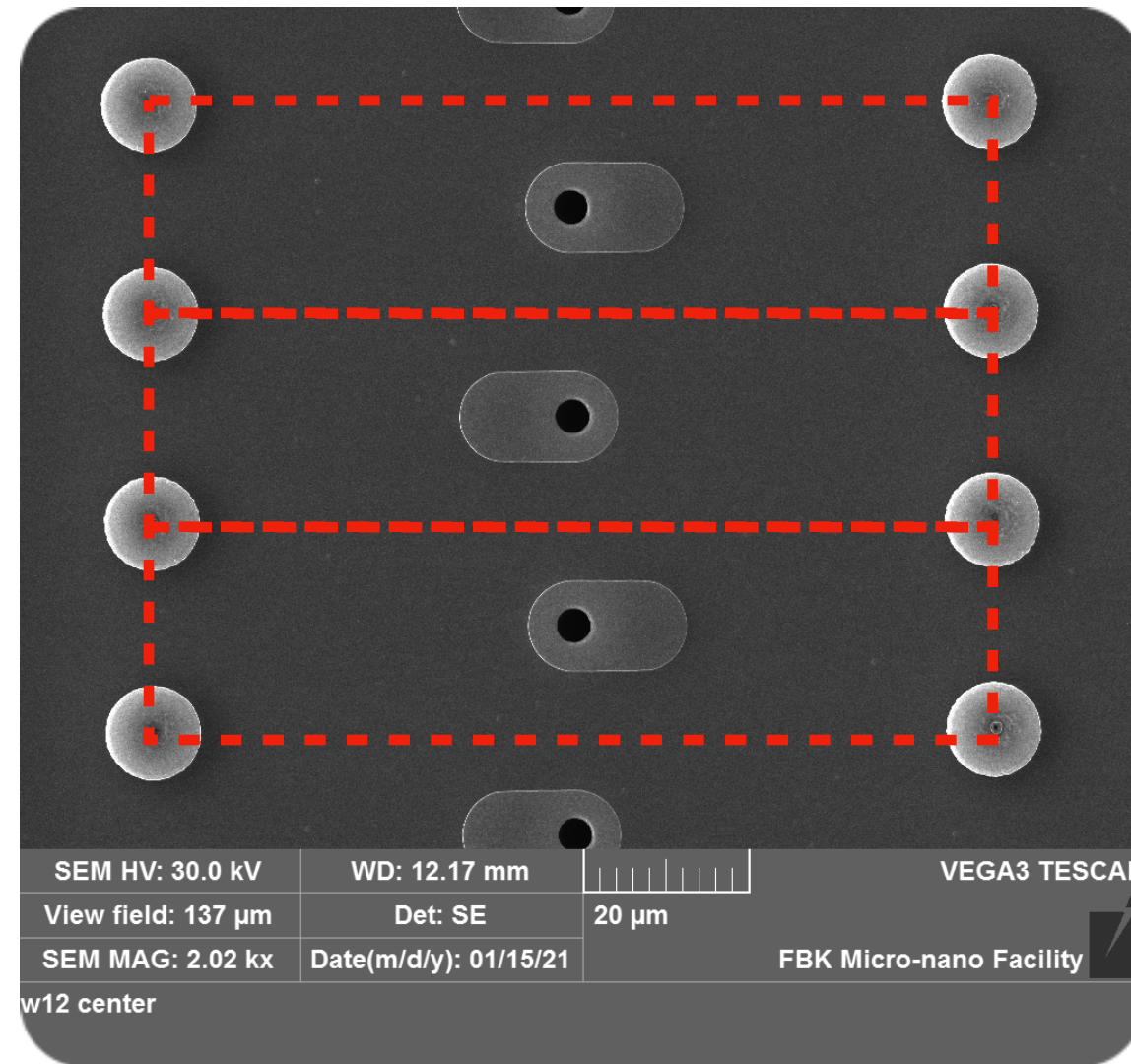


High resolution TEM image of two bonded wafers cross section

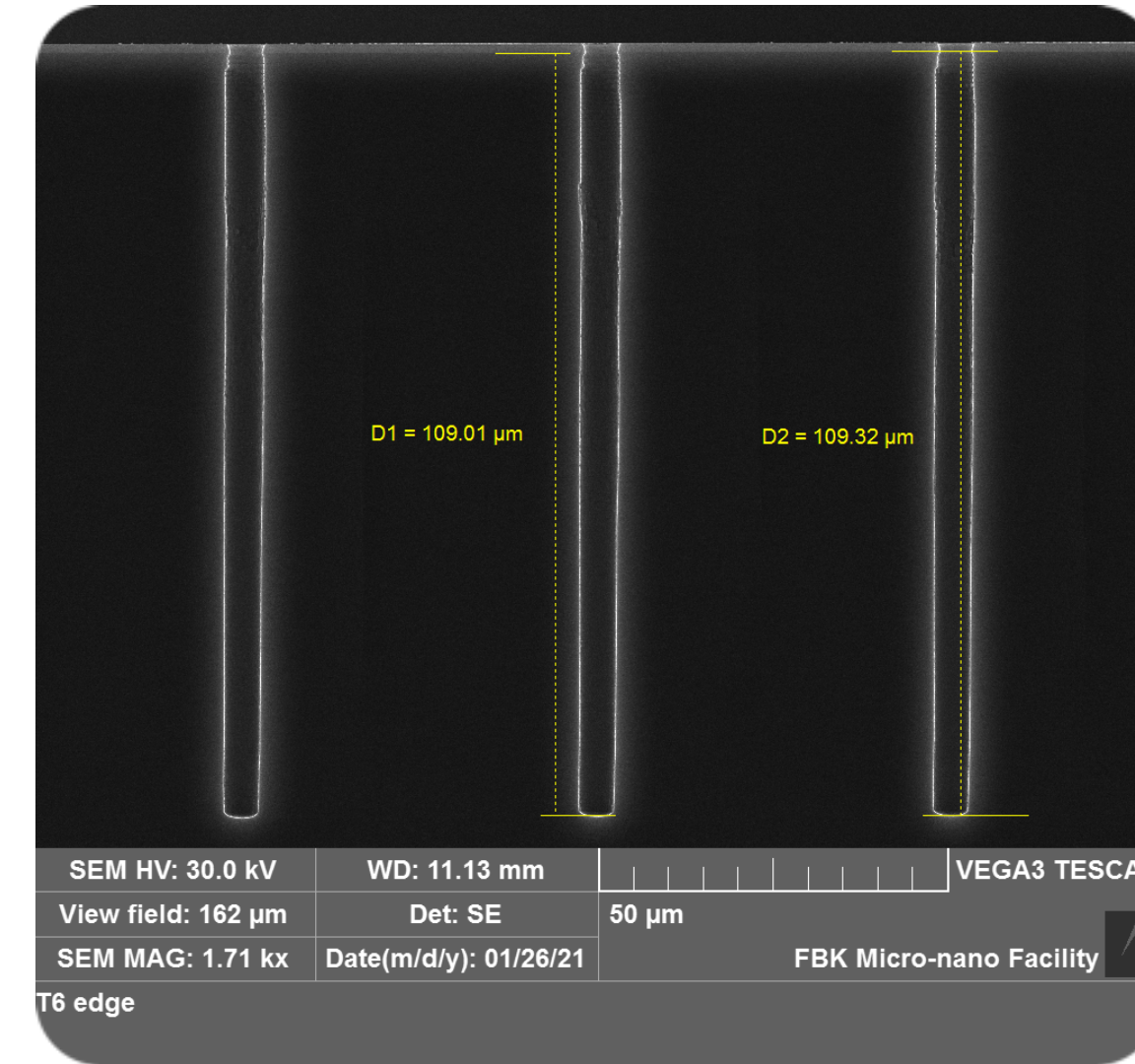
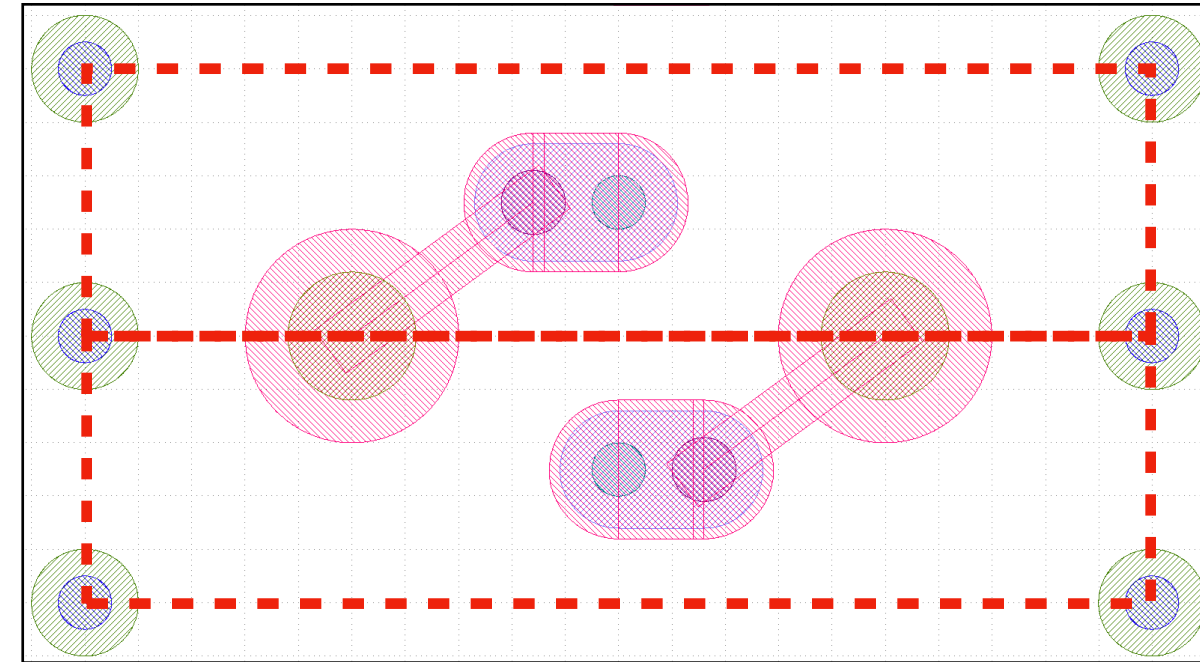
Columns produced by:

single-side **Deep Reactive Ion Etching - DRIE** process optimised by **FBK** (less expensive than double-side process)

Divide between layers →

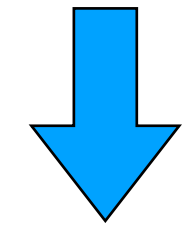


- **25x100 μm^2 pitch**
- Junction columns still to be filled with polysilicon



- **Column length $110 \pm 5 \mu\text{m}$**
- **1E, one junction column electrode per pixel cell**

Effective active layer
thickness reduced by *Boron*
diffusion from wafer carrier:
 $\sim 10 \mu\text{m}$



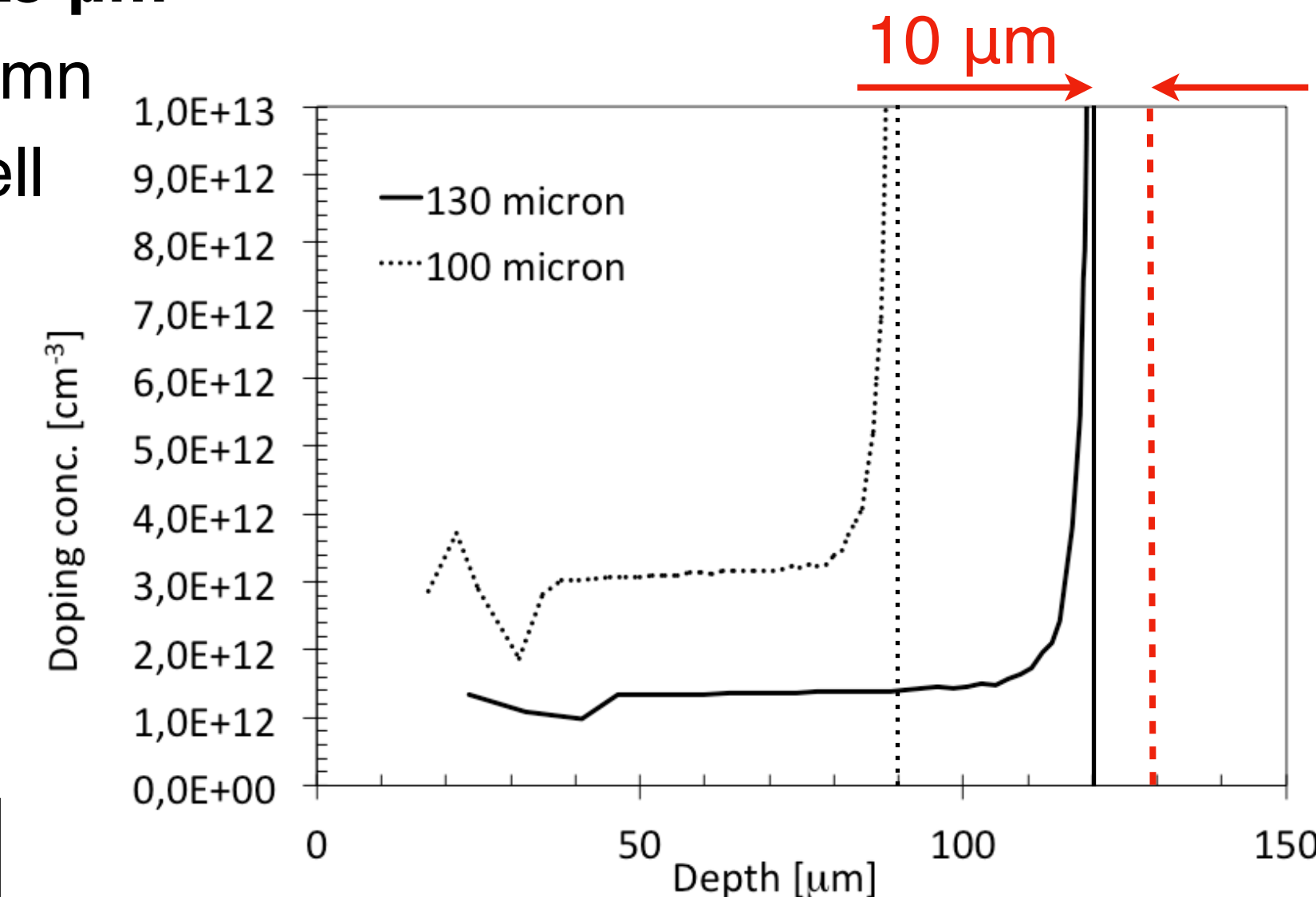
Expected **Most Probable Value**
- **MIP: $\sim 10190 e^-$ for $150 \mu\text{m}$**
active layer

Material kindly granted by FBK

- Sabina Ronchin
- Maurizio Boscardin
- Francesco Ficorella

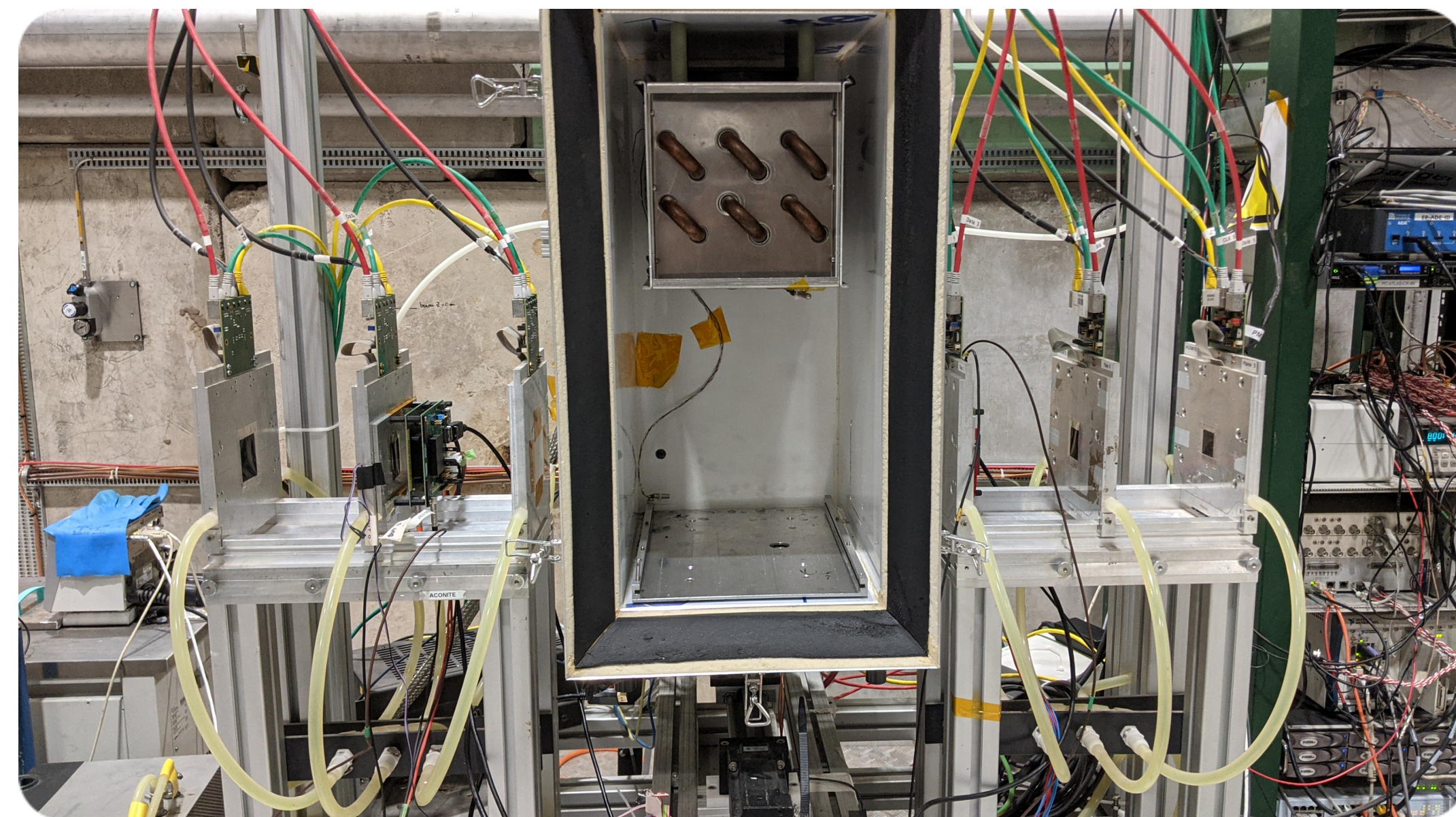
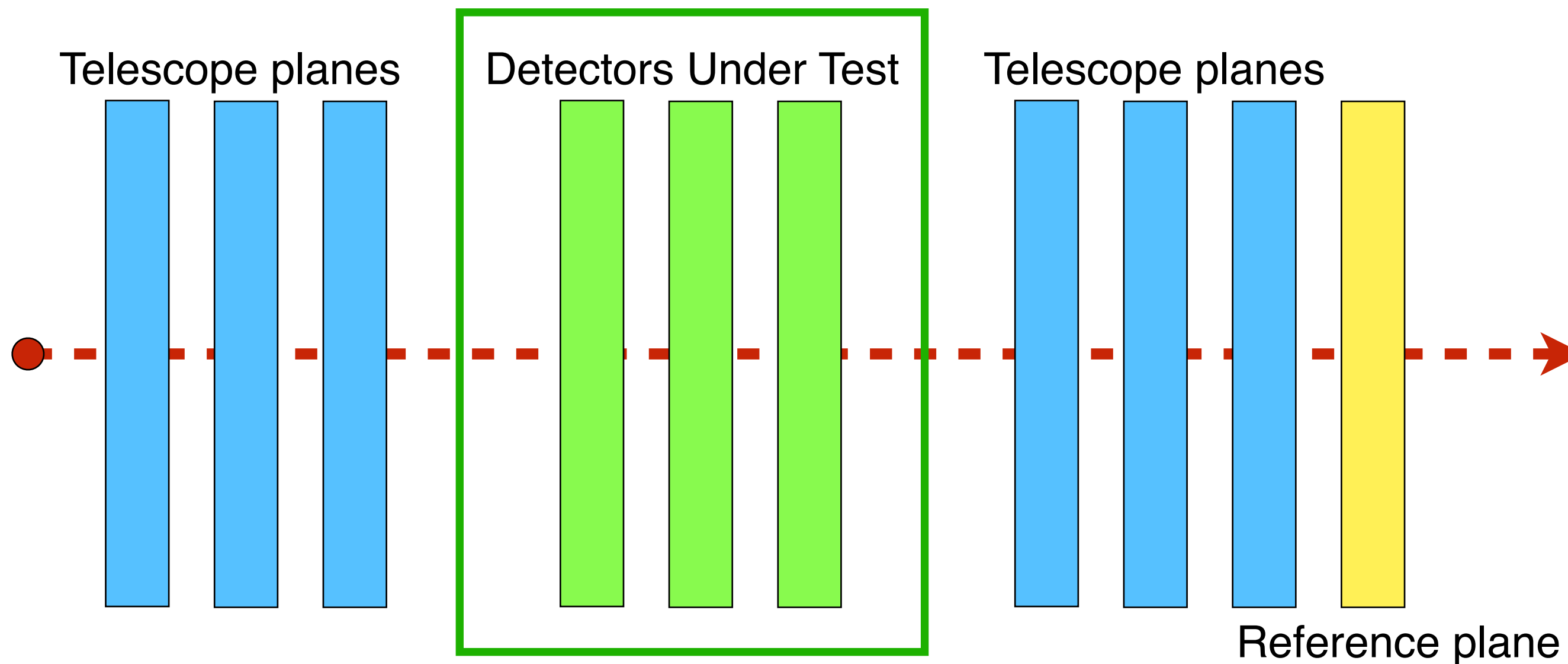


CNM sensors very similar to **FBK** but with
8 μm column diameter (see backup slides)



G.F. Dalla Betta et al., NIMA 824 (2016) 388

Readout chip and testbeam setup



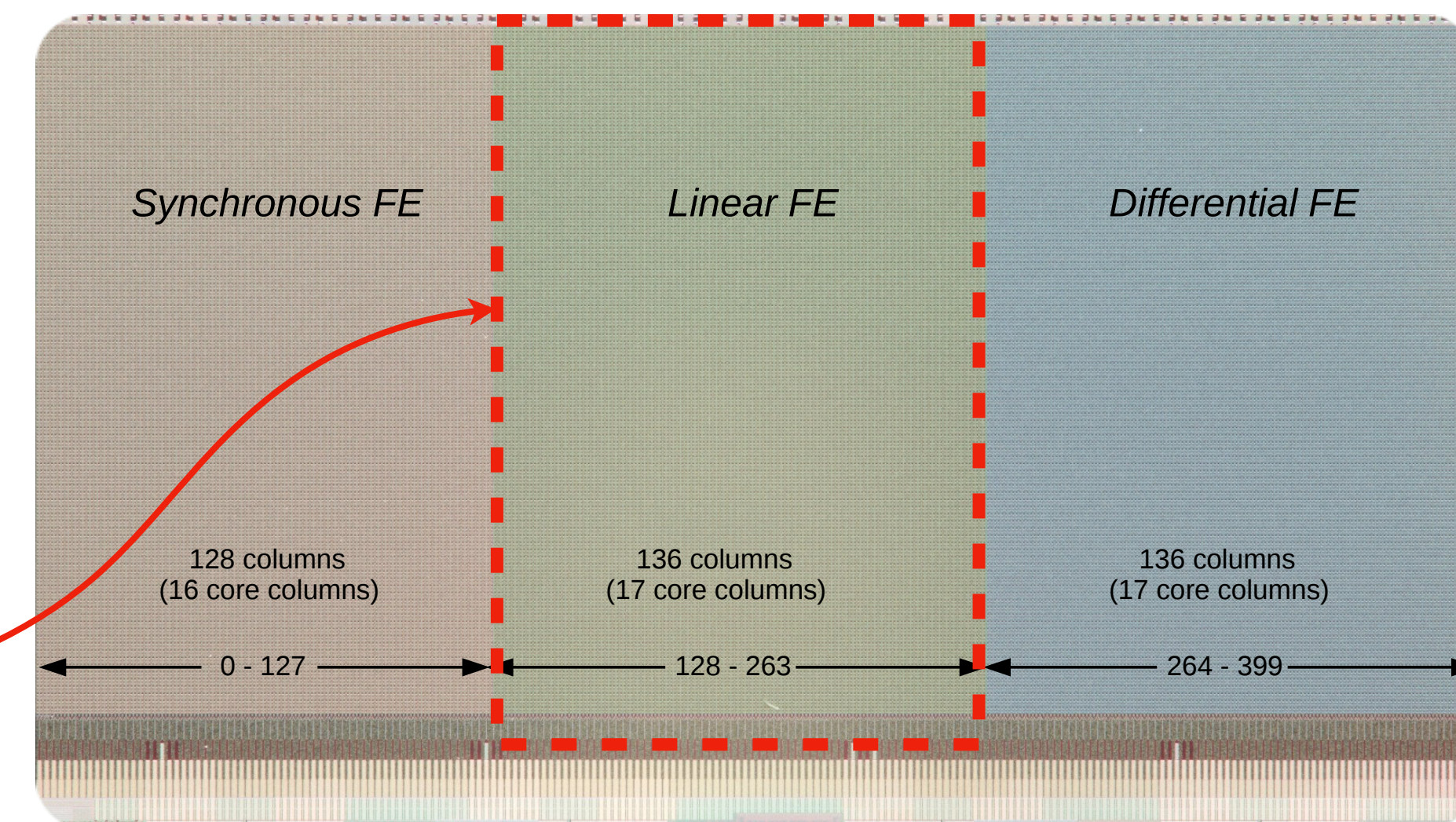
Jansen, H. et al., EPJ Techn Instrum 3, 7 (2016)

EUDET telescope on CERN SPS / DESY beam lines

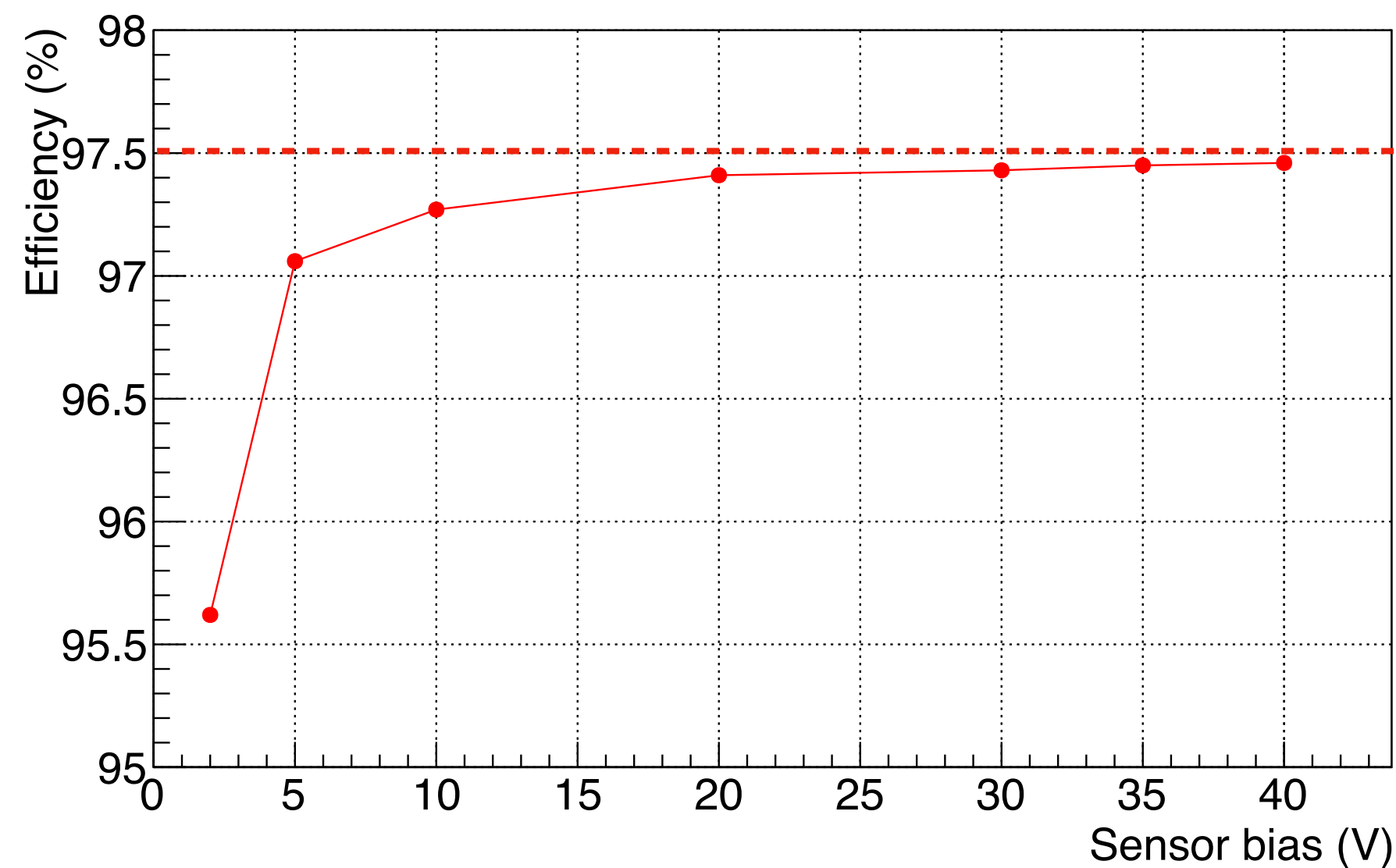
- 120 GeV pions (CERN) / 5.2 GeV electrons (DESY)
- 5 or 6 pixel planes (depending on beam-area)
- Based on Mimosa26 chip, 18.4 μm pitch, square pixels, 576 rows x 1152 columns
- **$\sim 2 \mu\text{m}$** resolution on each coordinate

ReadOut Chip (ROC)

- Common CMS-ATLAS R&D (**RD53A**): 65 nm CMOS technology
- 3 frontends, CMS chose linear-frontend: **192** rows x **136** columns
- Readout multiple bunch crossings
- Global threshold with **per pixel 4 bit threshold trimming**
- **Time-over-Threshold** hit charge measurement with **4 bits ADC**

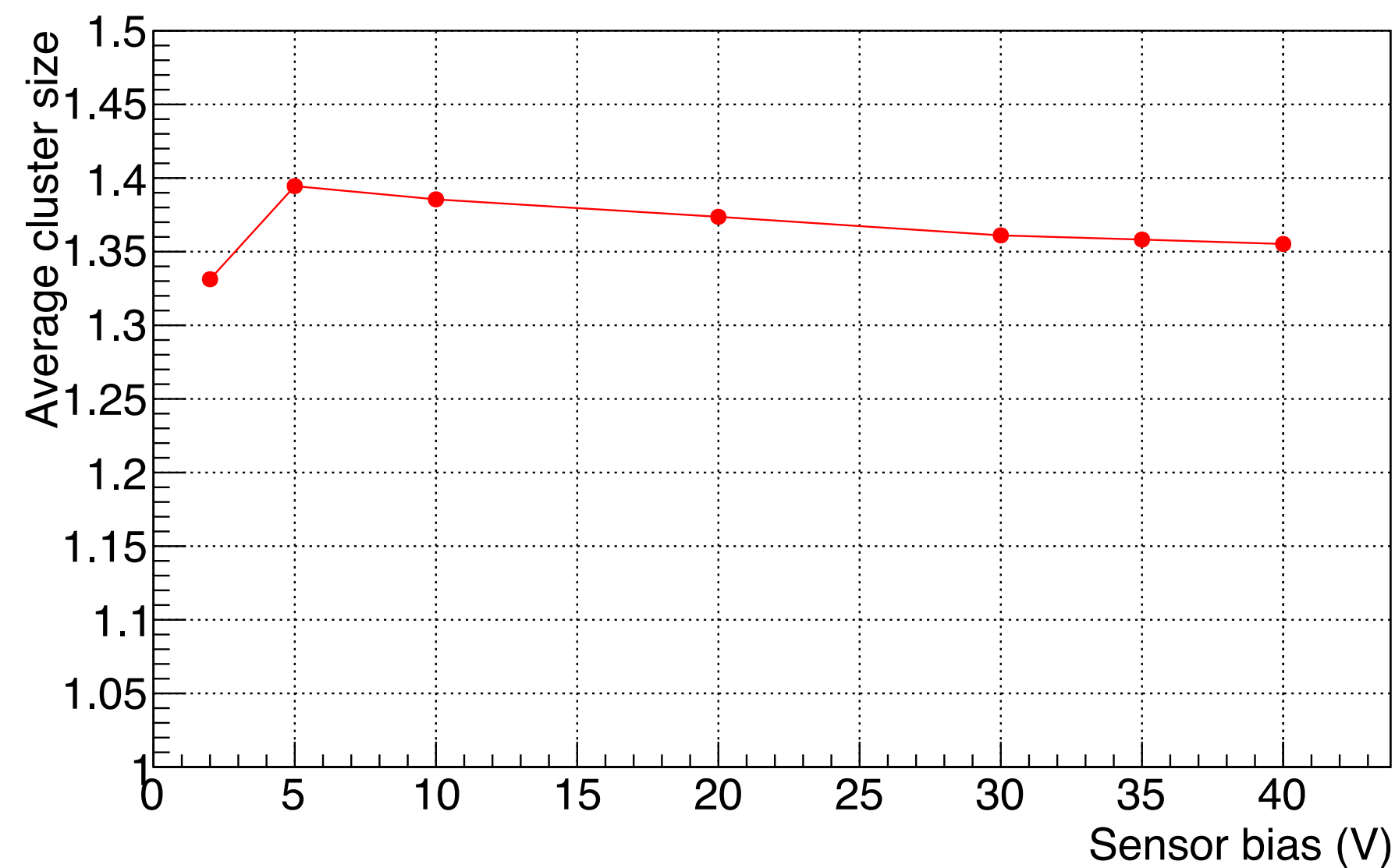


Readout chip prototype **RD53A**



Efficiency stops at 97.5%:

- Ohmic column inefficiency
- 4-pixel sharing and relatively high threshold

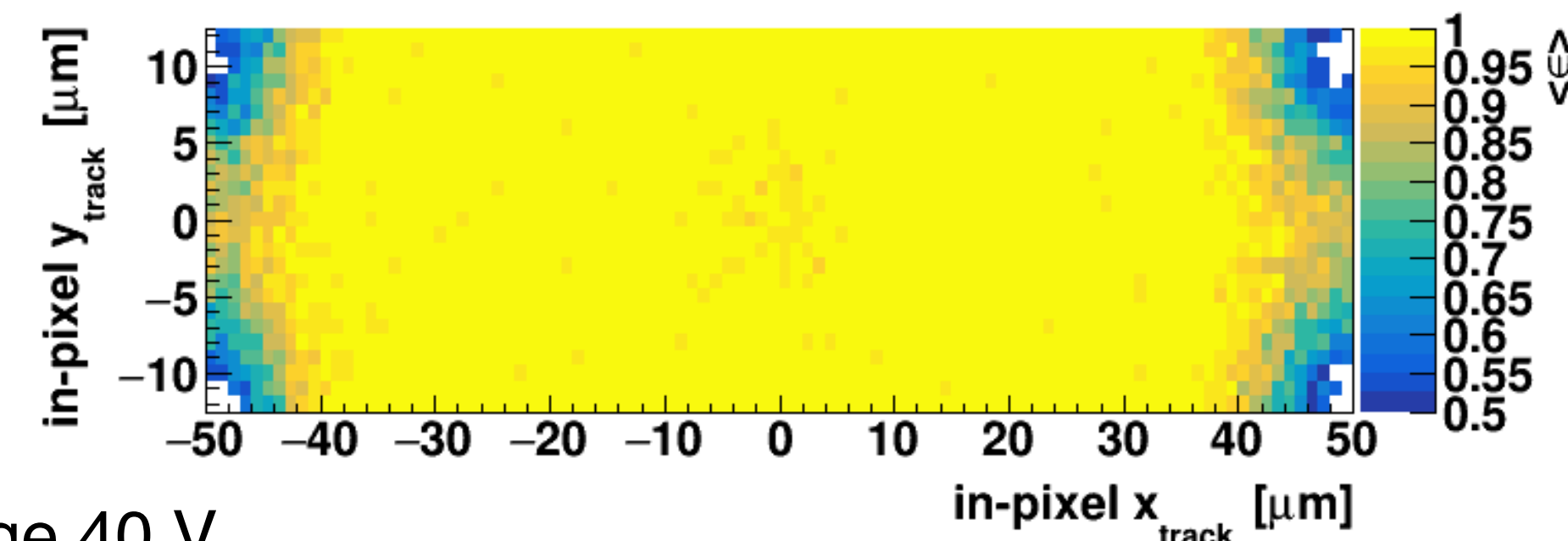


All data shown refers to:

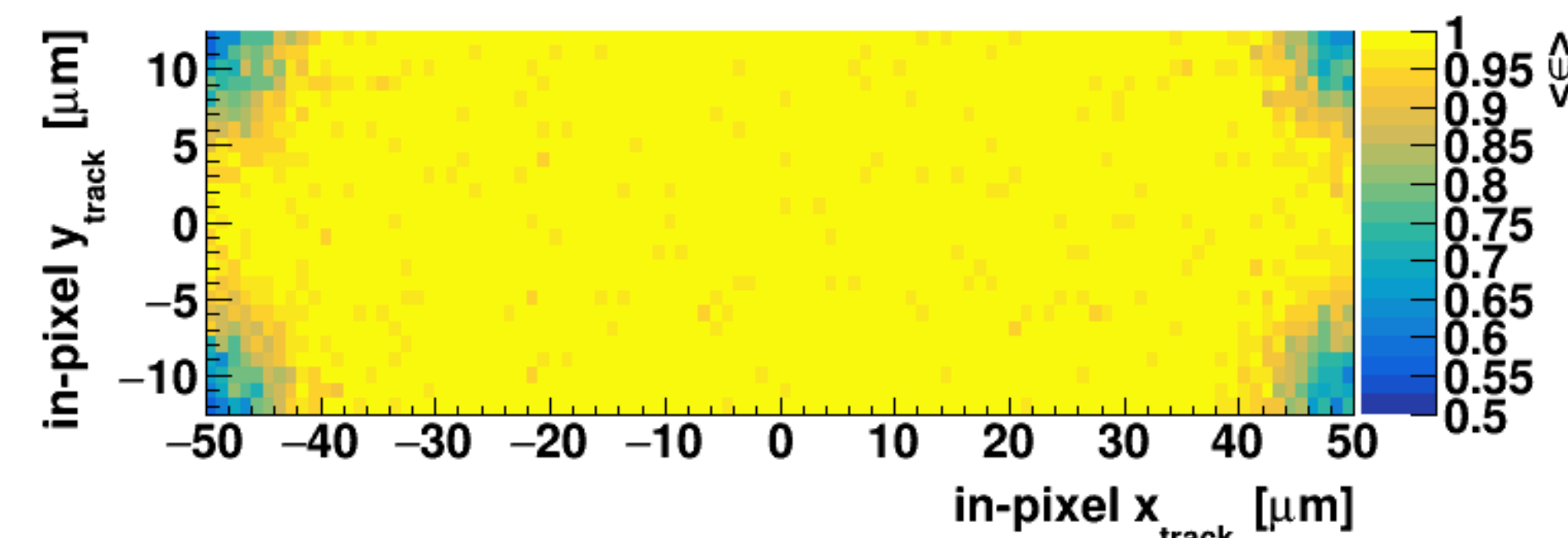
- Normal incidence
- Threshold **2500 e⁻**

Bias voltage 2 V

Efficiency maps in pixel cell

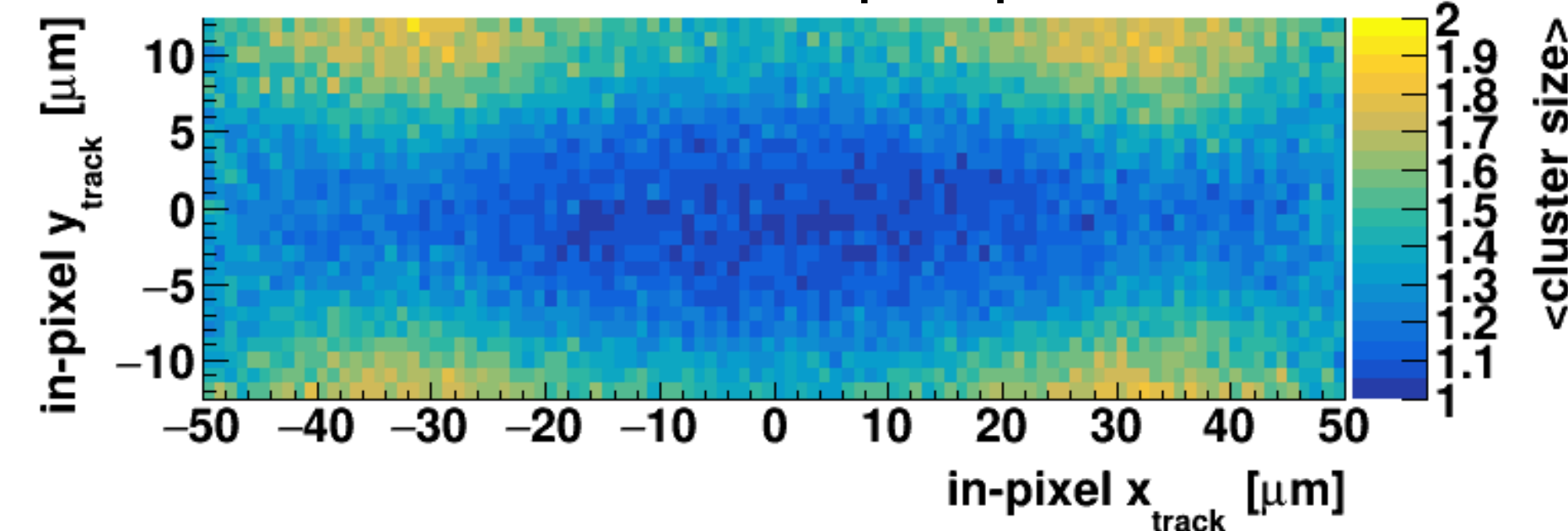


Bias voltage 40 V



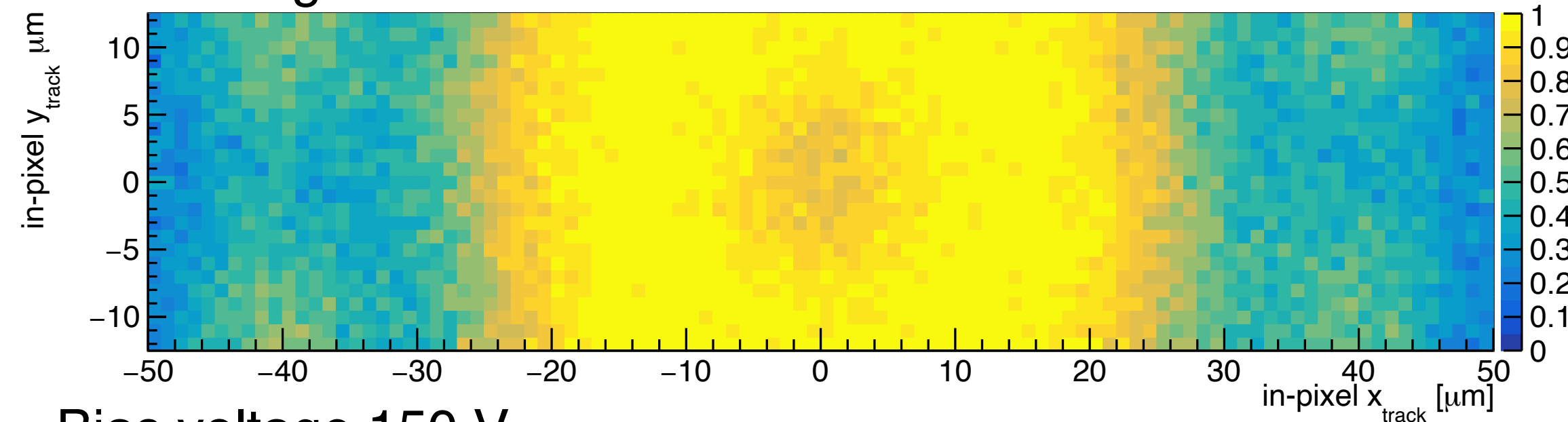
Bias voltage 40 V

Cluster size map in pixel cell

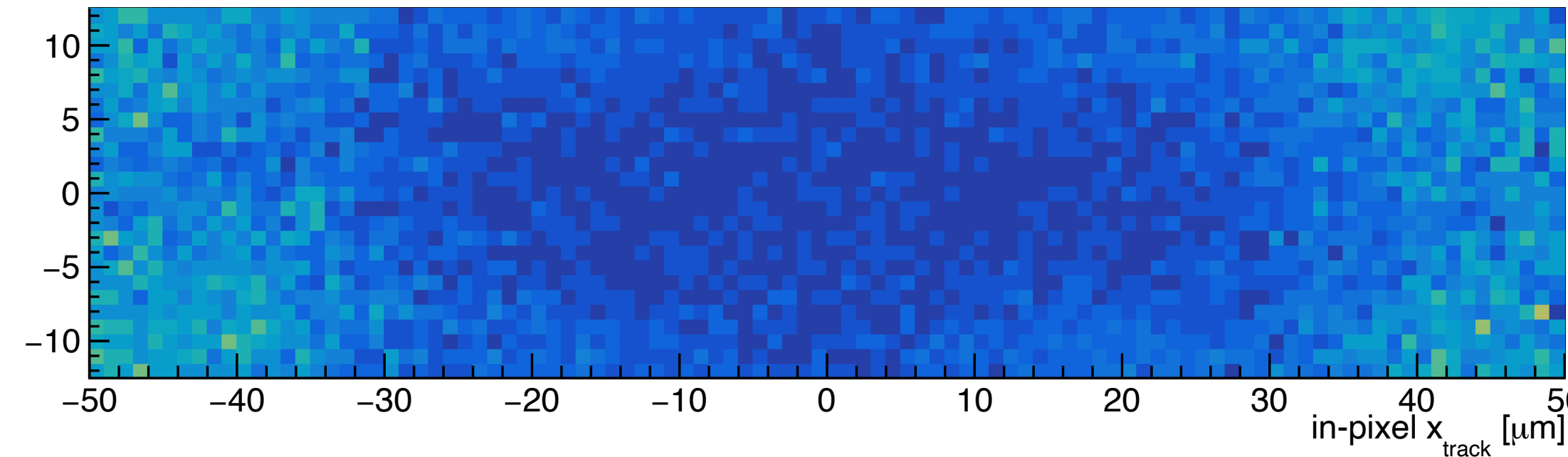


*Results from irradiated 3D **CNM** will be available very soon*

Bias voltage 50 V

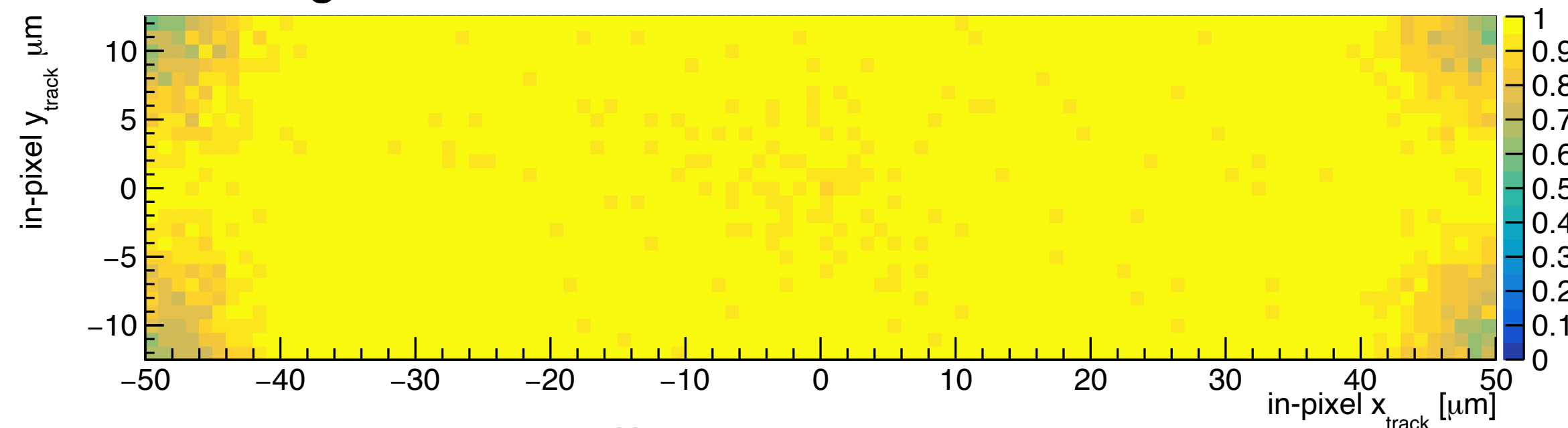


U

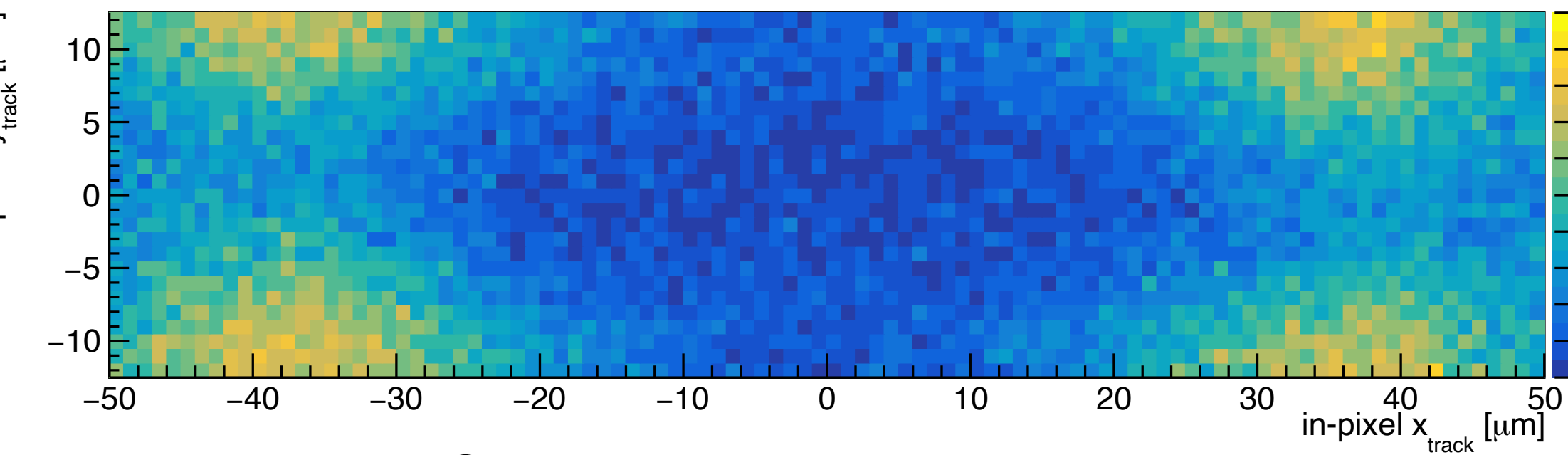
in-pixel y_{track} [μm]

<pixels/cluster>

Bias voltage 150 V



U

in-pixel y_{track} [μm]

<pixels/cluster>

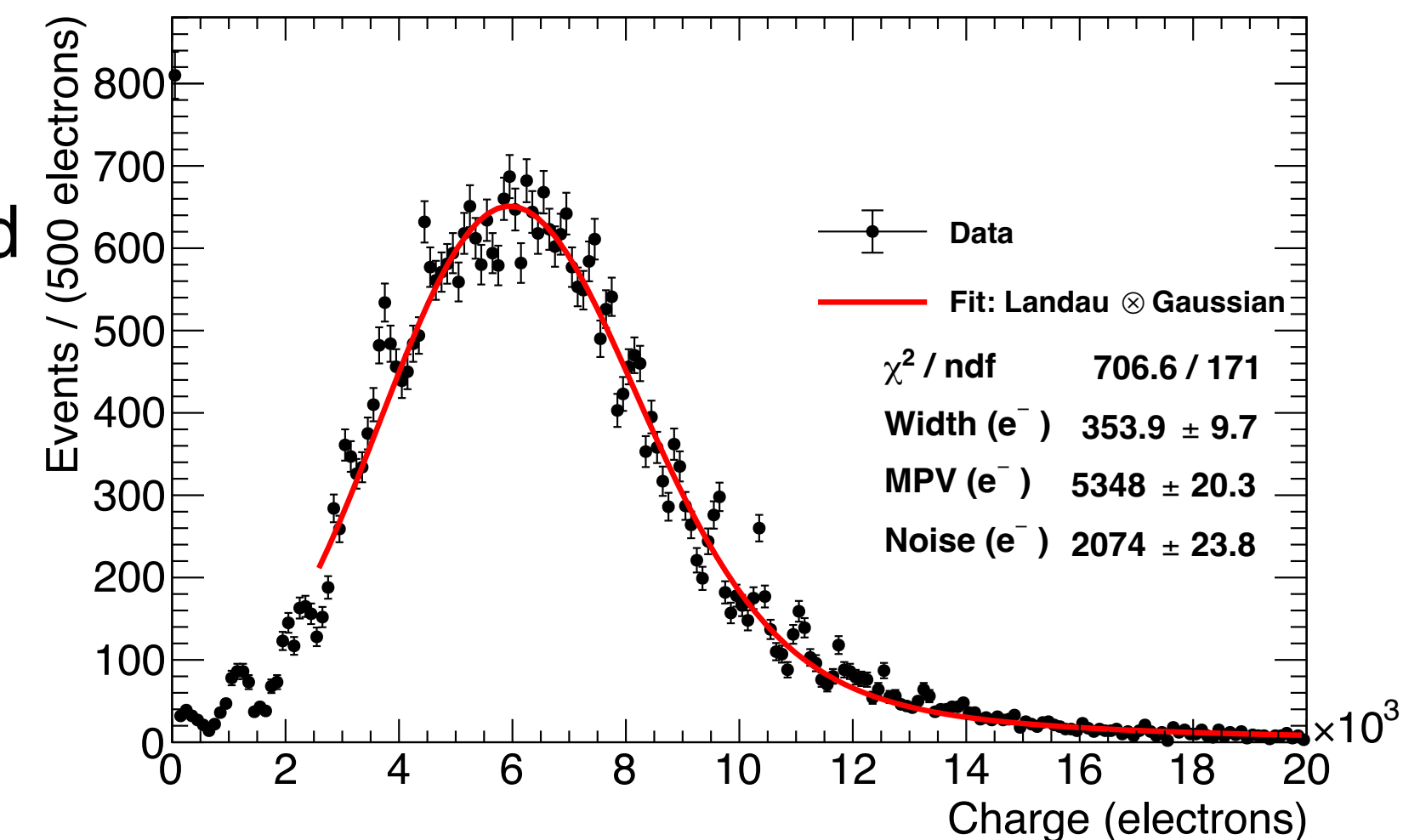
Efficiency map in pixel cell

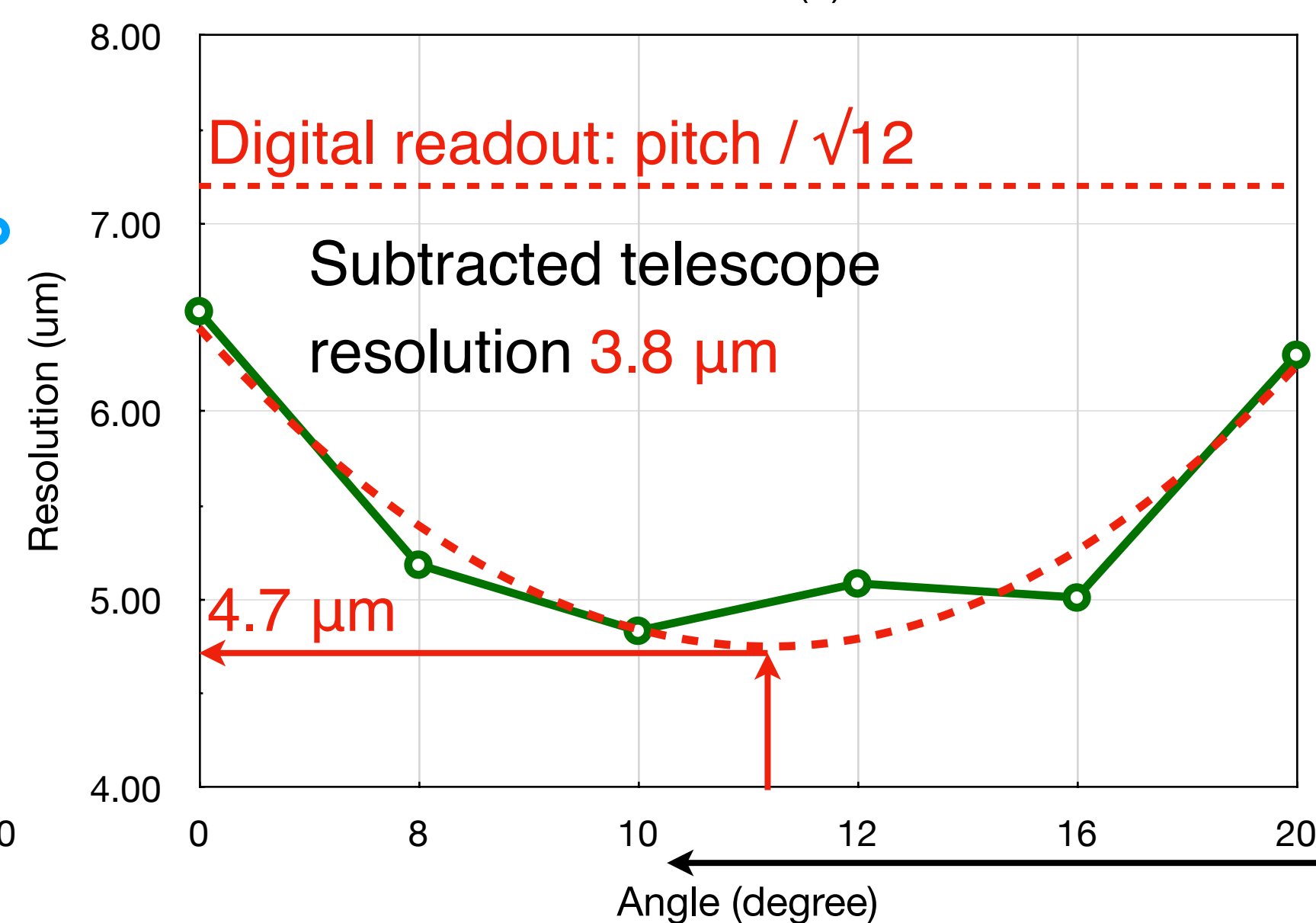
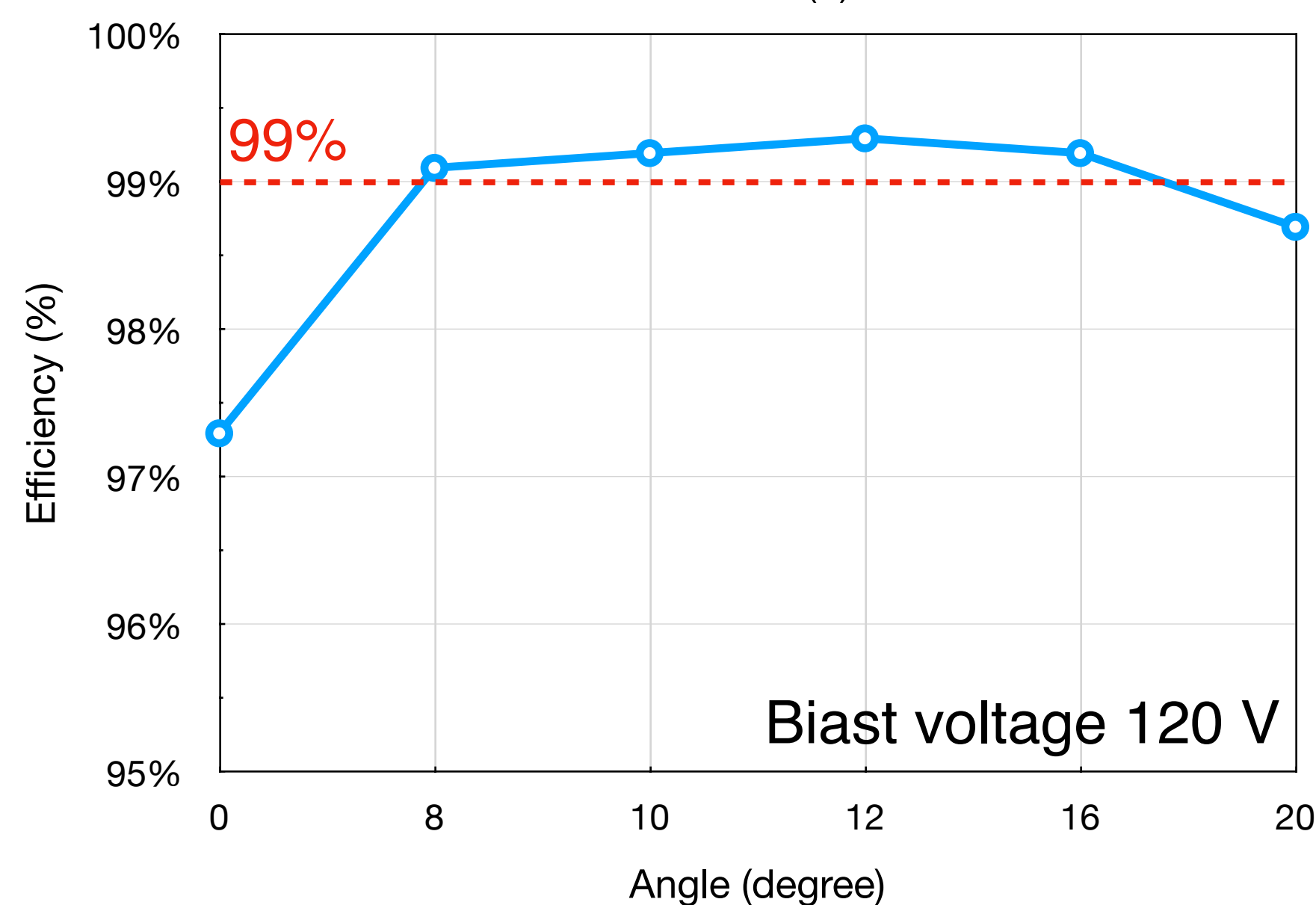
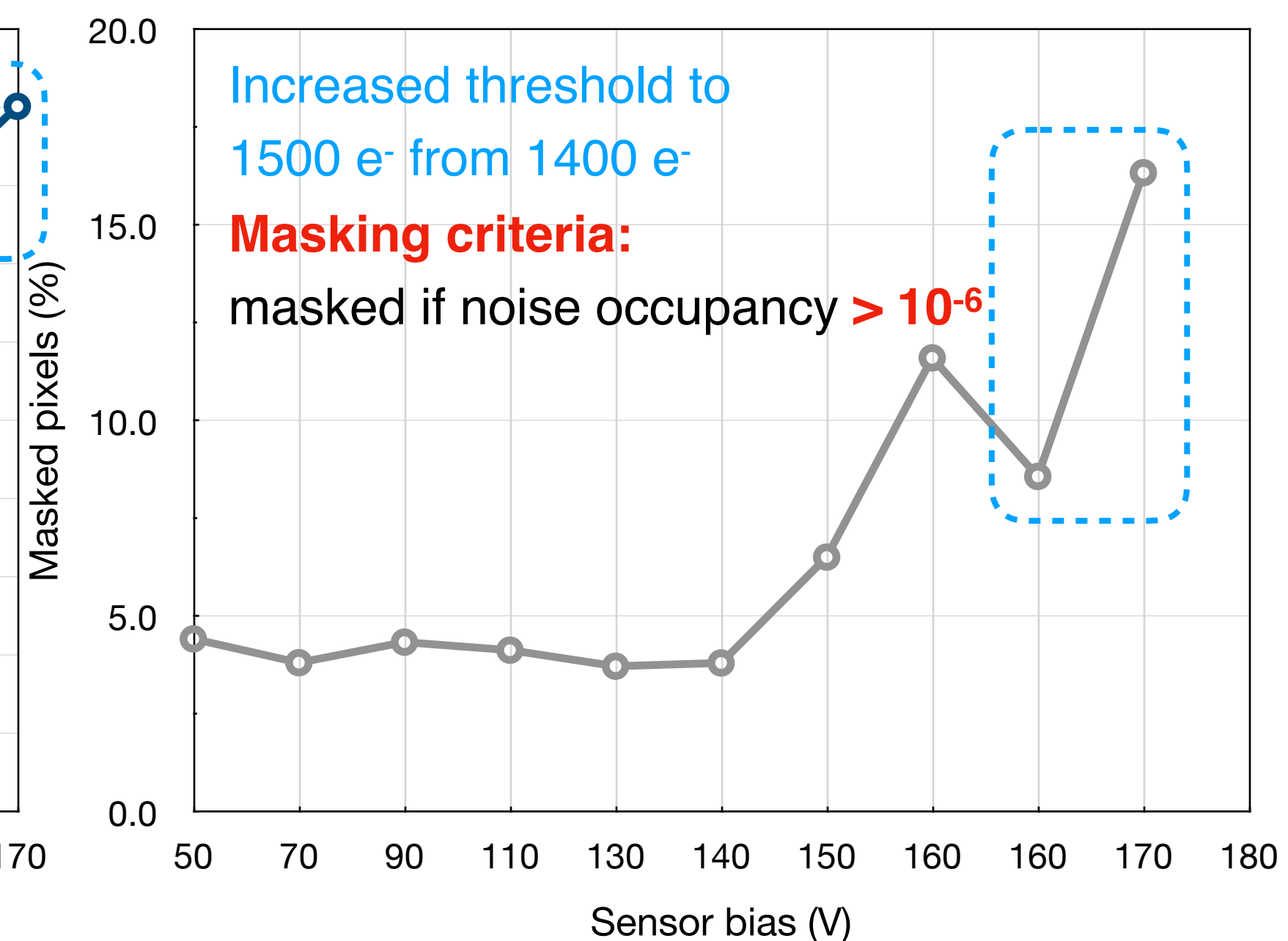
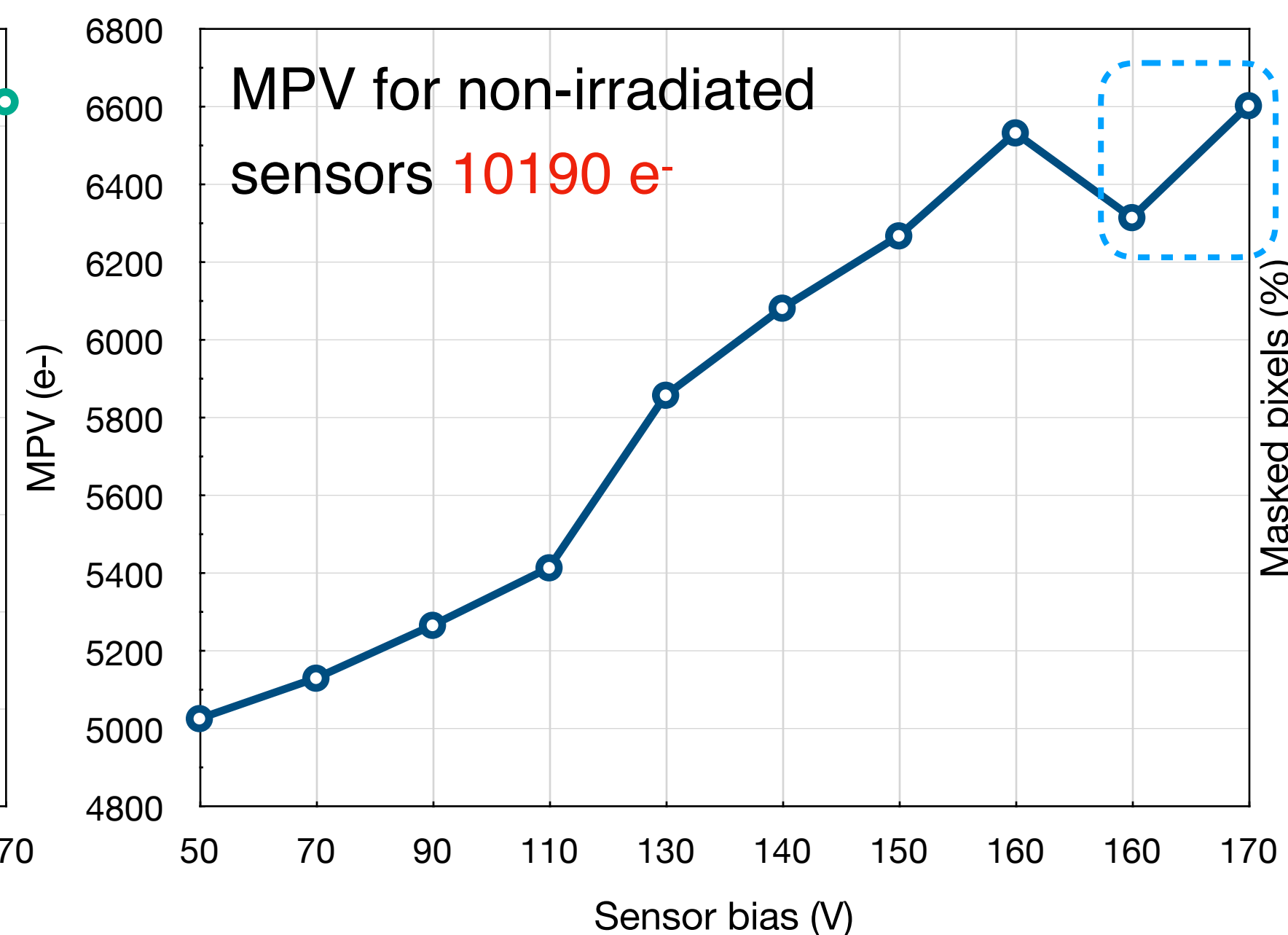
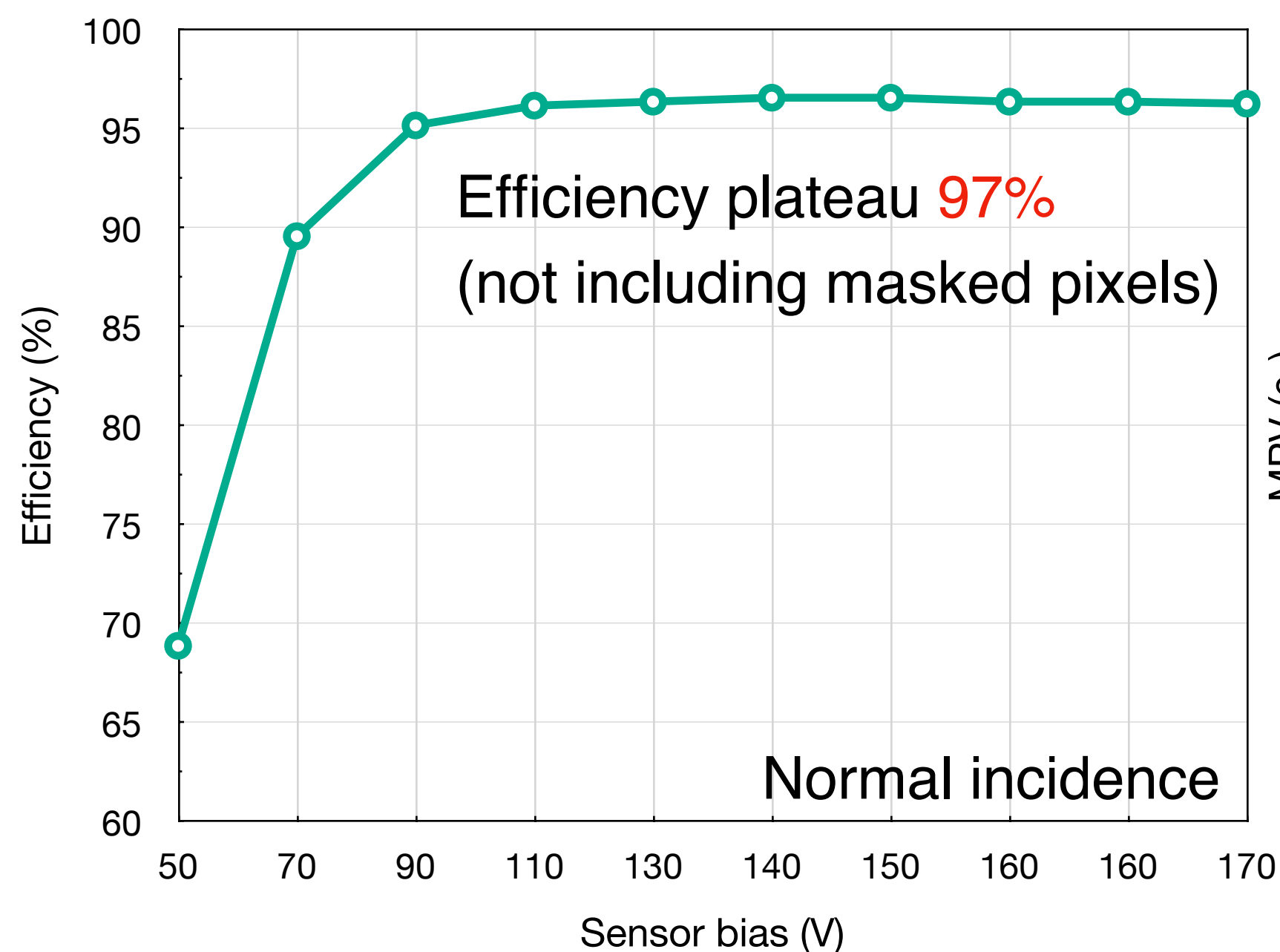
Cluster size map in pixel cell

All data shown refers to:

- Normal incidence
- Threshold **1400 e⁻**
- Irradiated at $1.5 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$ at **KIT** (25 MeV protons, **uniform irradiation**)
- Temperature -30/-20°C (near sensor)

Landau distribution measured
at bias voltage 120 V





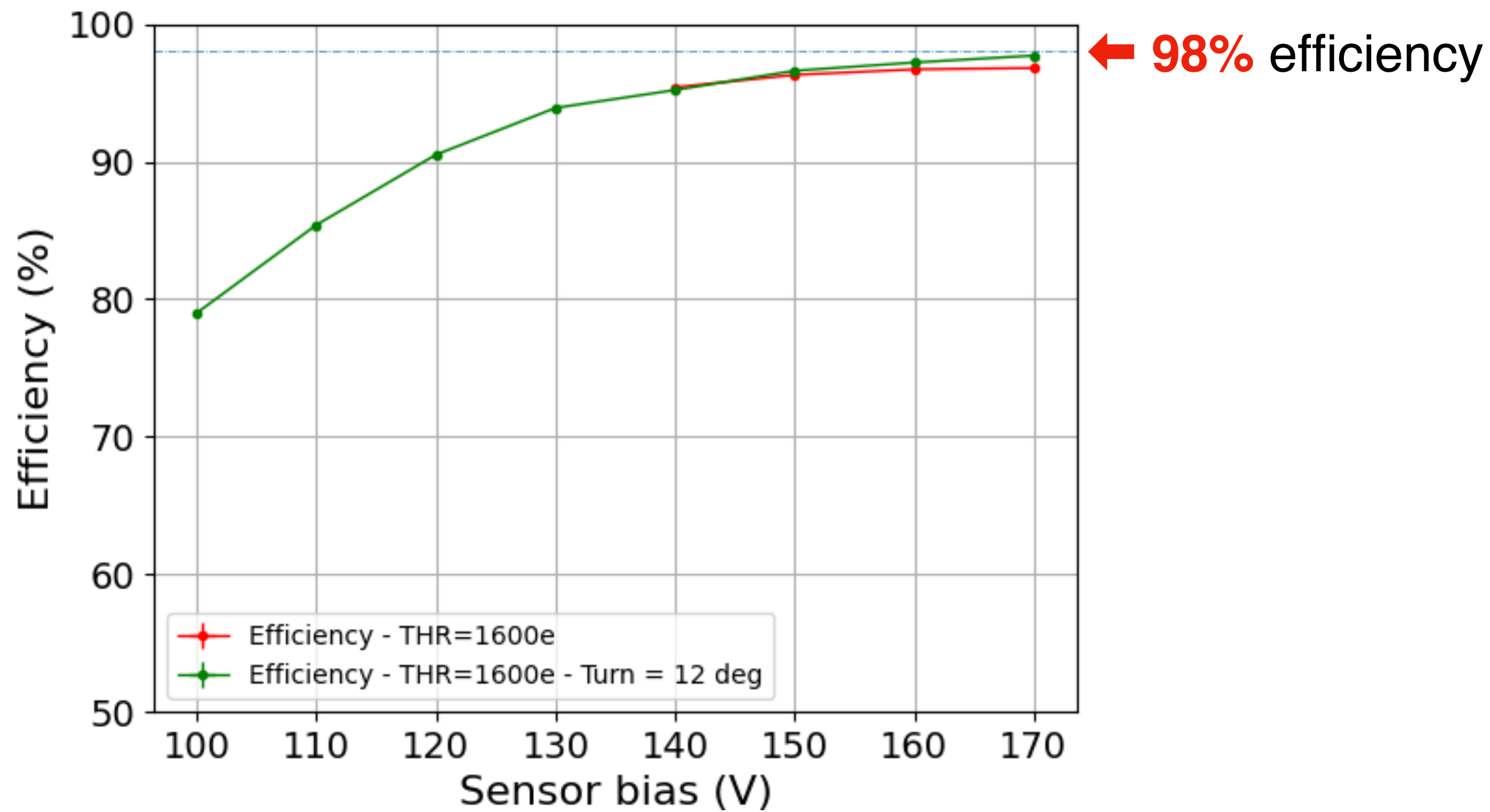
Relatively high number of masked pixels \rightarrow under investigation



Can be mitigated by increasing the threshold, as backup plan a replacement of barrel layer 1 can be foreseen when needed, maybe earlier than anticipated

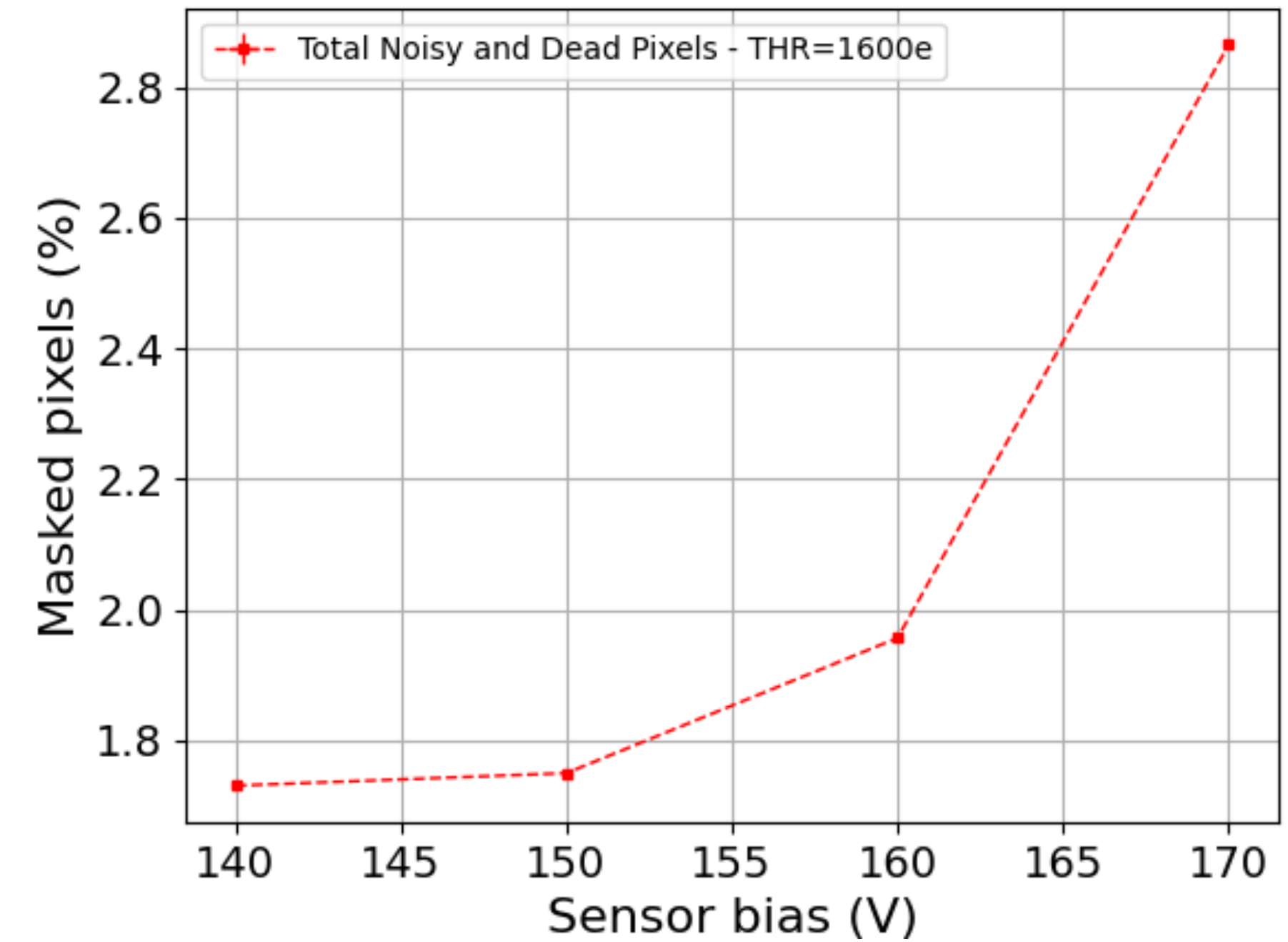


Best resolution expected at $\arctan(25/140)$
 ≈ 10 degrees



Efficiency vs sensor bias
(not including masked pixels)

- **normal incidence**
- **12° incidence angle**



Masked pixels vs sensor bias

Masking criteria:

masked if noise occupancy $> 2 \times 10^{-5}$

All data shown refers to:

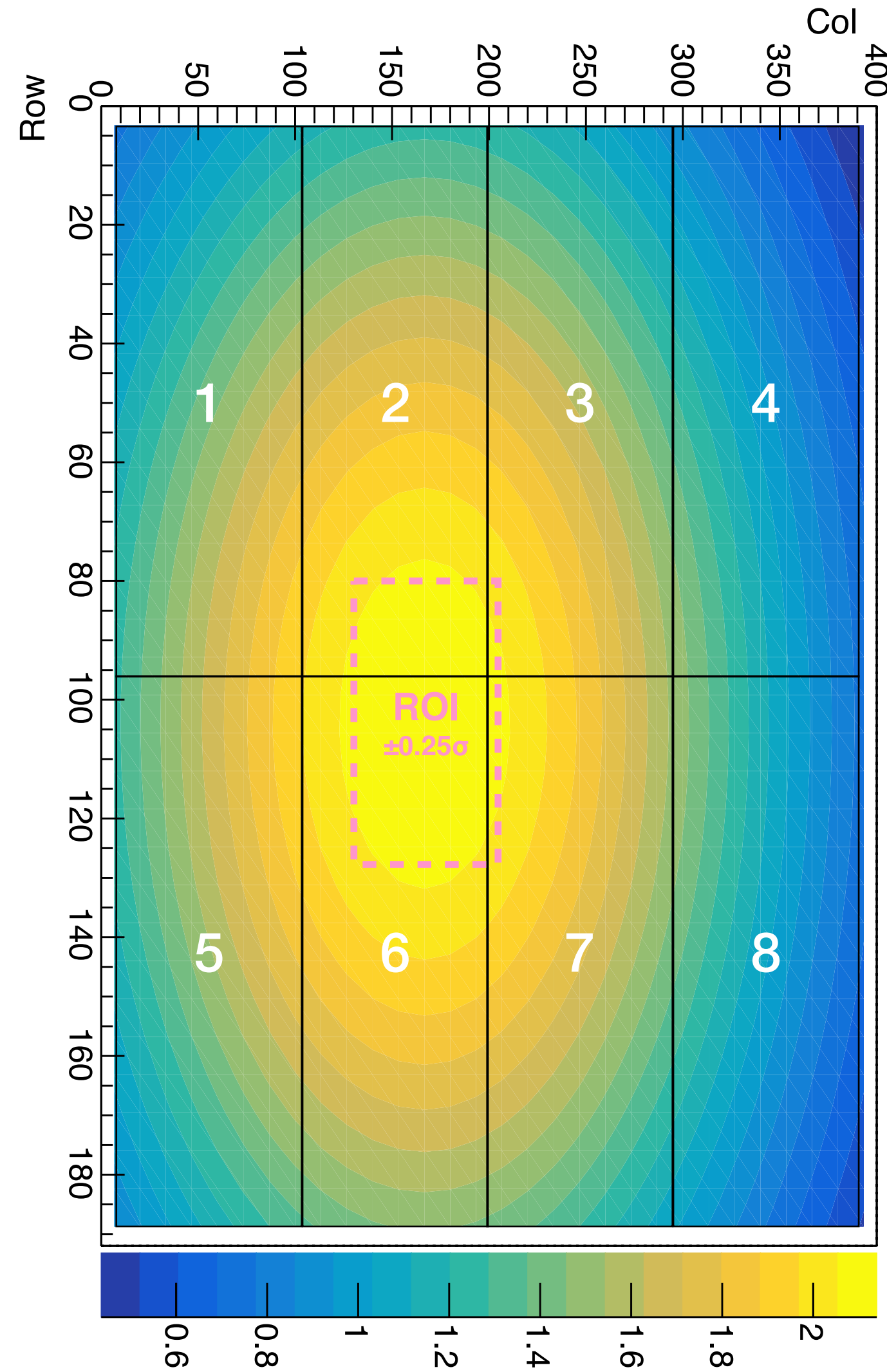
- Threshold **1600 e⁻**
- Irradiated at $1.8 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$ at **KIT** (25 MeV protons, **uniform irradiation**)
- Temperature -20°C (near sensor)

Results: 3D **FBK** irradiated at $2.1\text{--}2.6 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$

Irradiated at **CERN PS** (24 GeV protons, beam narrower than sensor size)

Dosimetry evaluation

1. Aluminum foil placed on sensor surface during irradiation campaign
2. Cut into **8** pieces and measured activity
3. Fit with bivariate Normal distribution
 - no correlation
 - constraints on widths
 - constraint on position along rows
4. Define a **Region Of Interest - ROI** of \sim uniform irradiation



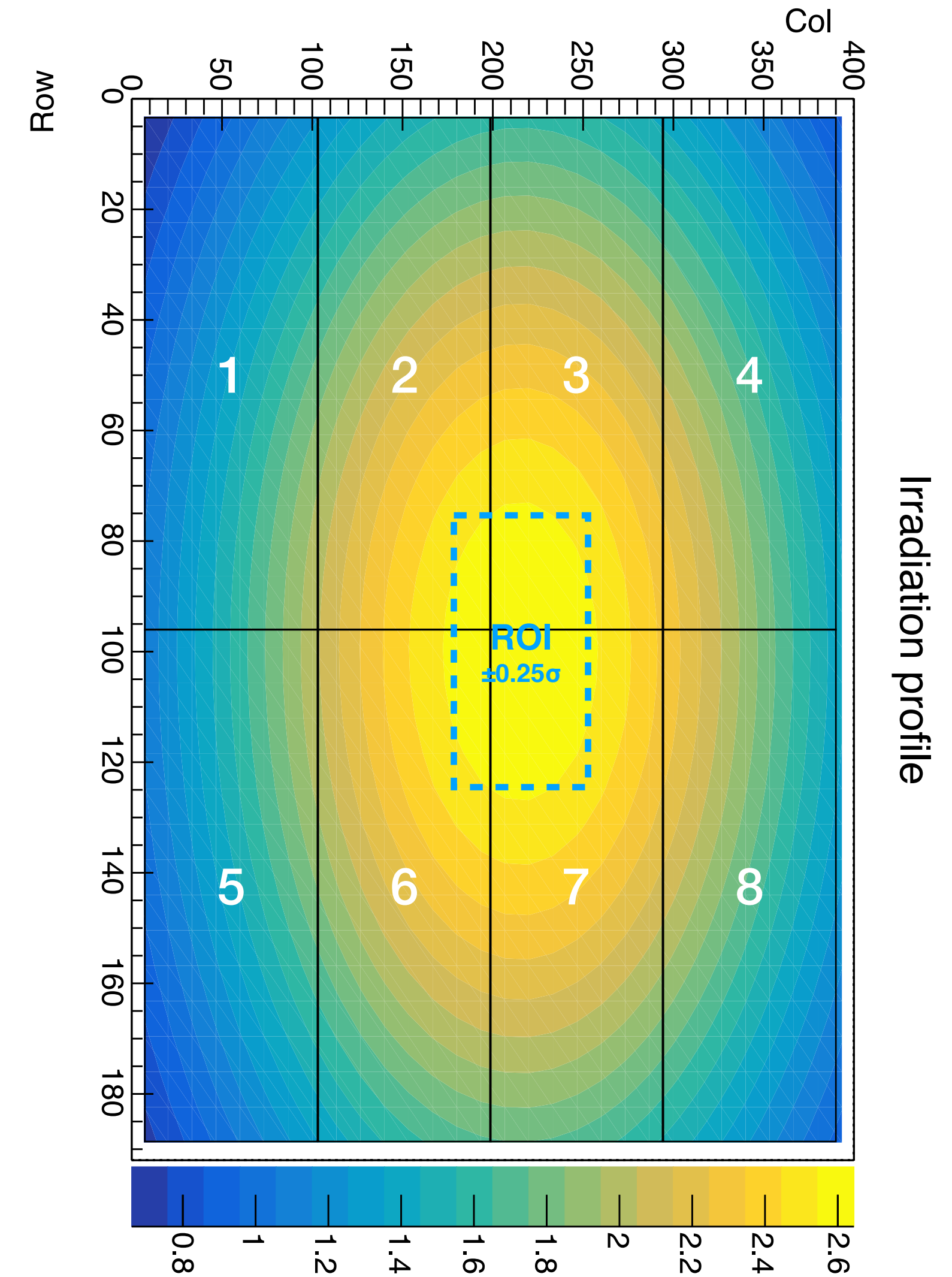
Irradiation profile

Standard deviation of fluence in ROI



Irradiation profile on sensor surface

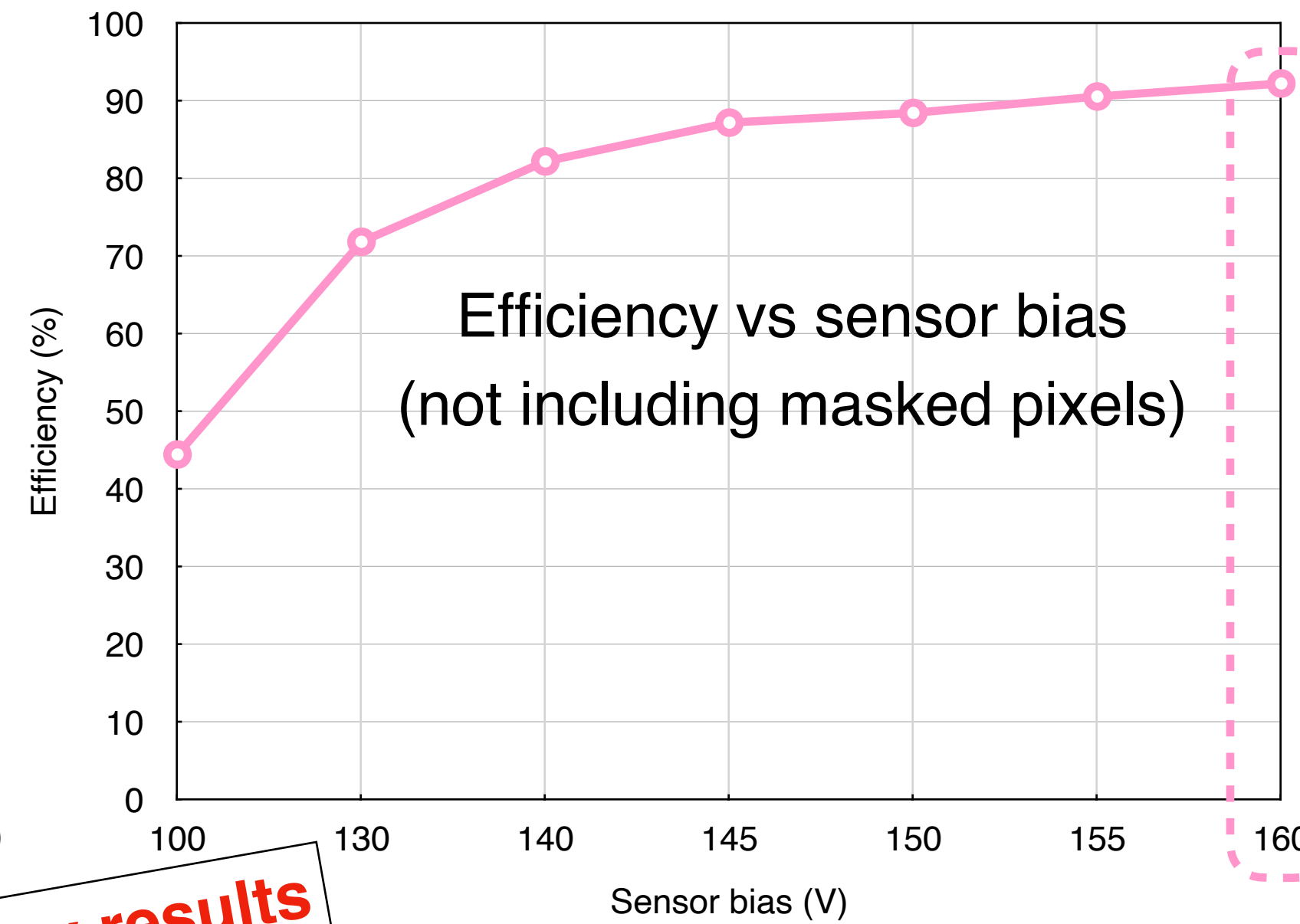
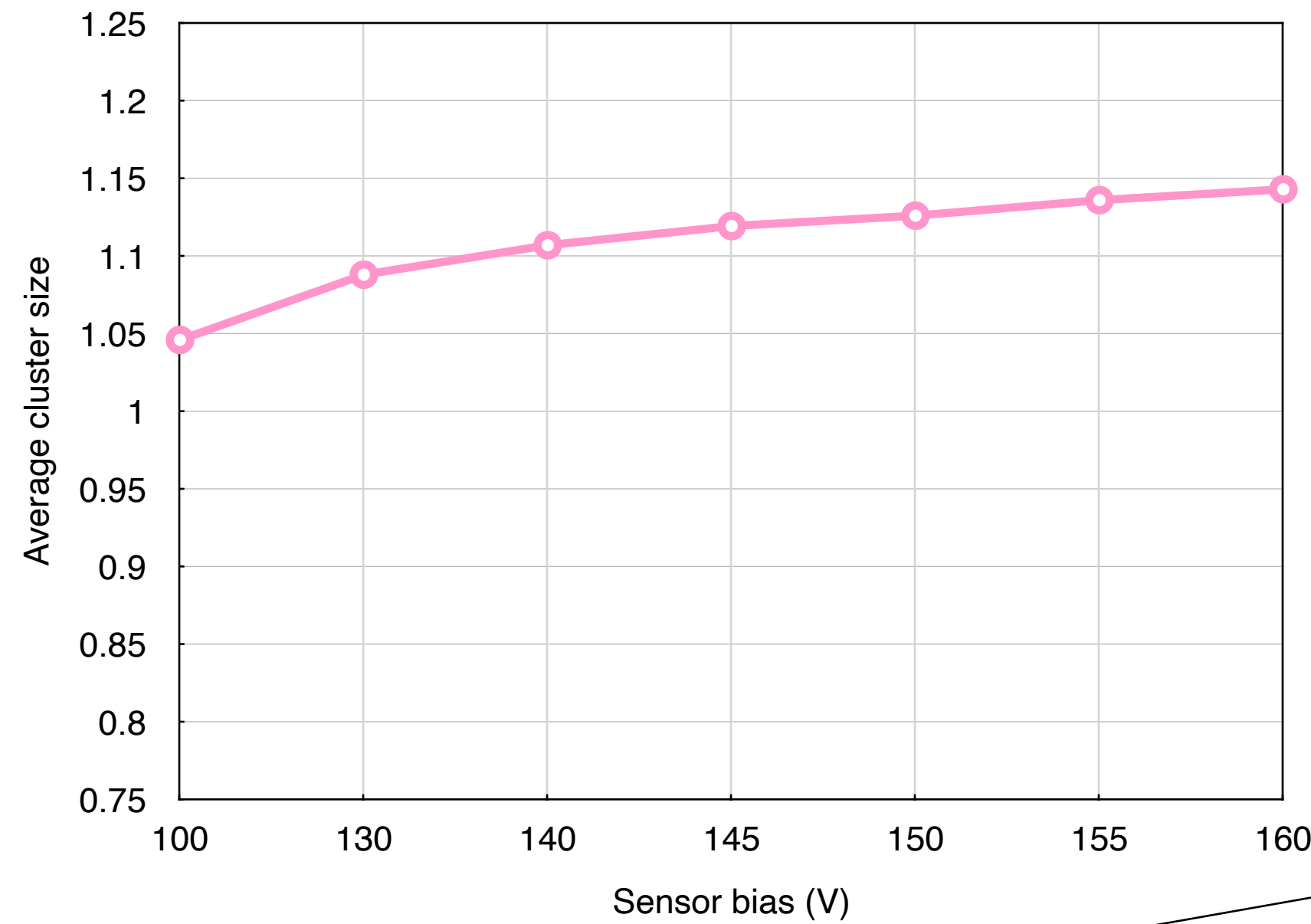
ROI ($\pm 0.25\sigma$): $(2.10 \pm 0.08) \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$, variability 0.03



Irradiation profile

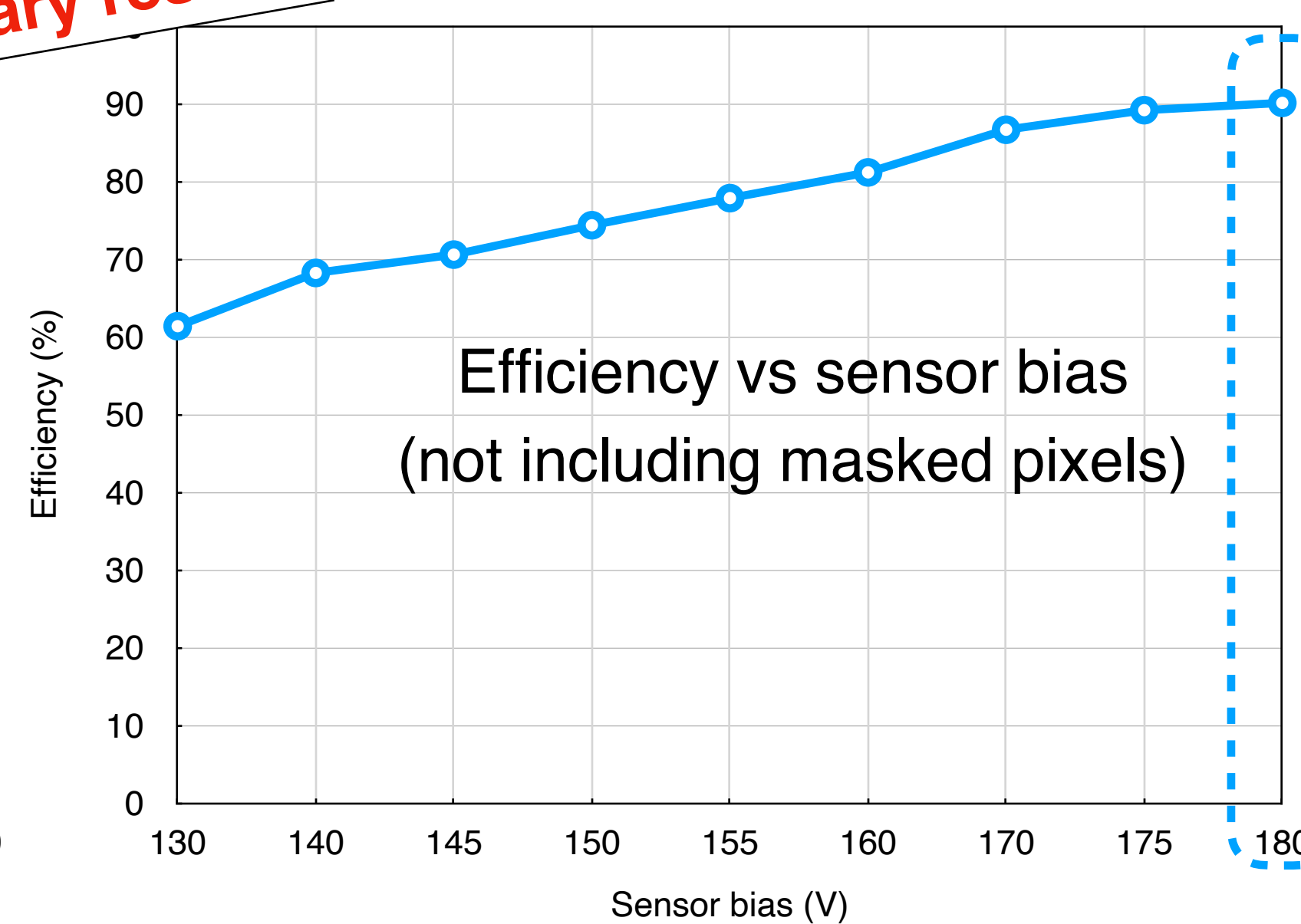
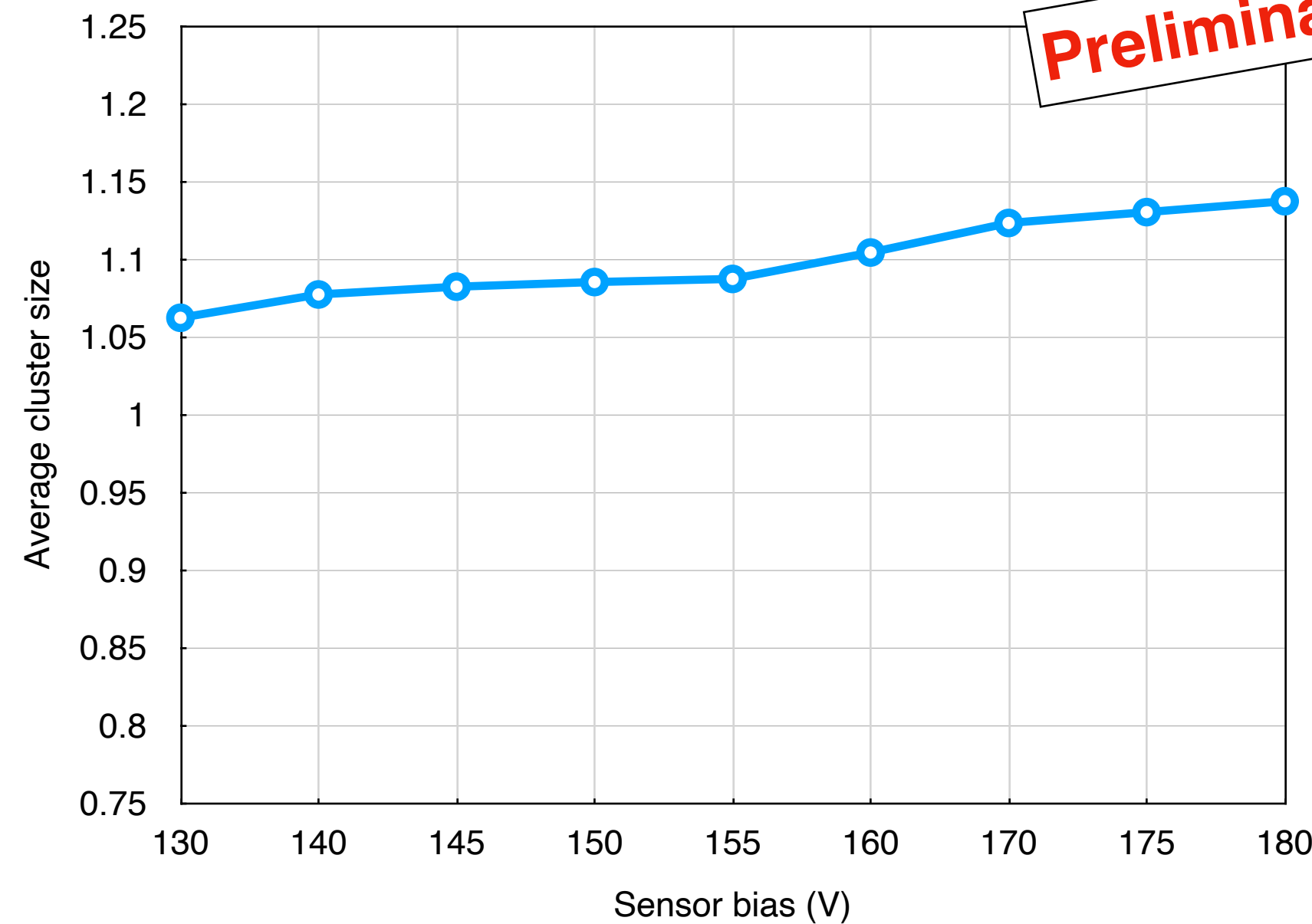
Irradiation profile on sensor surface

ROI ($\pm 0.25\sigma$): $(2.60 \pm 0.09) \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$, variability 0.03

Results: 3D **FBK** irradiated at $2.1\text{--}2.6 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$ 

- Normal incidence
- Fluence in ROI (2.10 ± 0.08) $\times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$, variability 0.03
- Threshold **2000 e^-**

- Efficiency 92%
- Masked pixels $\sim 7\%$



- Normal incidence
- Fluence in ROI (2.60 ± 0.09) $\times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$, variability 0.03
- Threshold **1900 e^-**

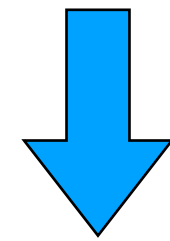
- Efficiency 90%
- Masked pixels $\sim 4\%$

Masking criteria:
masked if noise occupancy $> 2 \times 10^{-5}$

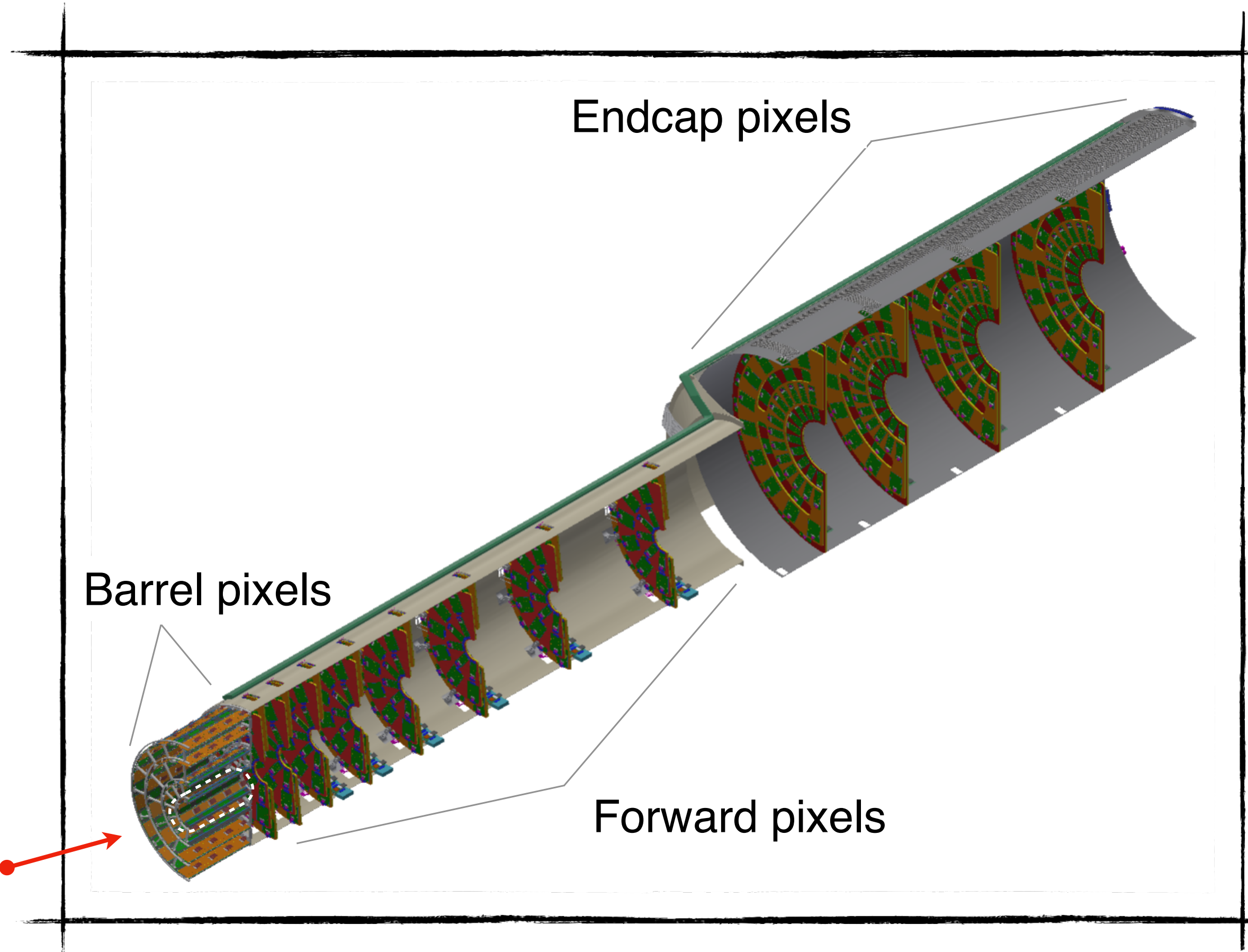
Preliminary results

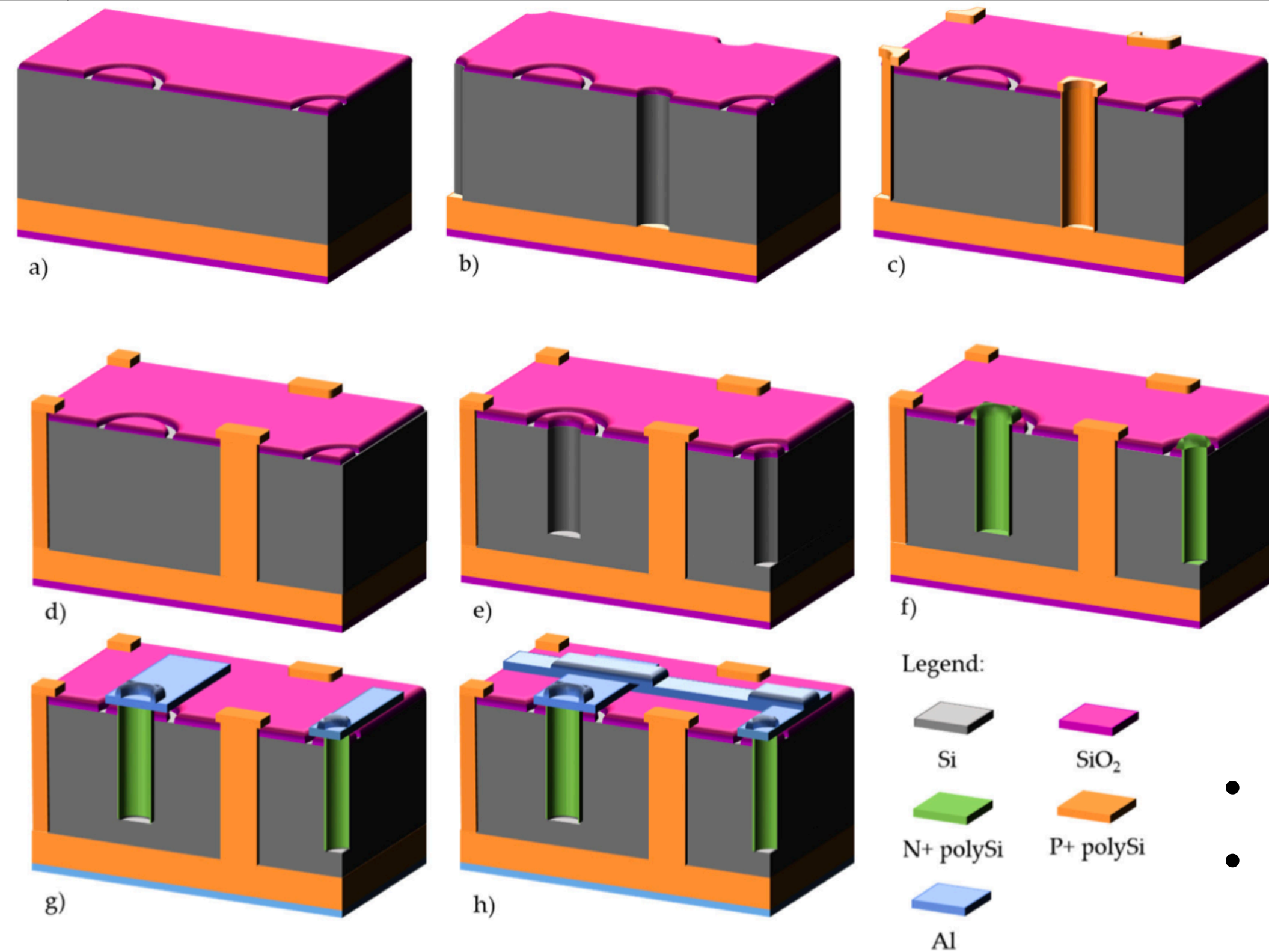
We presented the status of the CMS **3D sensor R&D**

- **3D pixels** are baseline choice for **barrel layer 1**
- Tested at different fluencies up to **$2.6 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$**
- Overall performances are extremely encouraging
 - * Large increase of noisy pixels vs bias at fluences **$>1.5 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$** under investigation
- Need to test with the final version of the readout chip



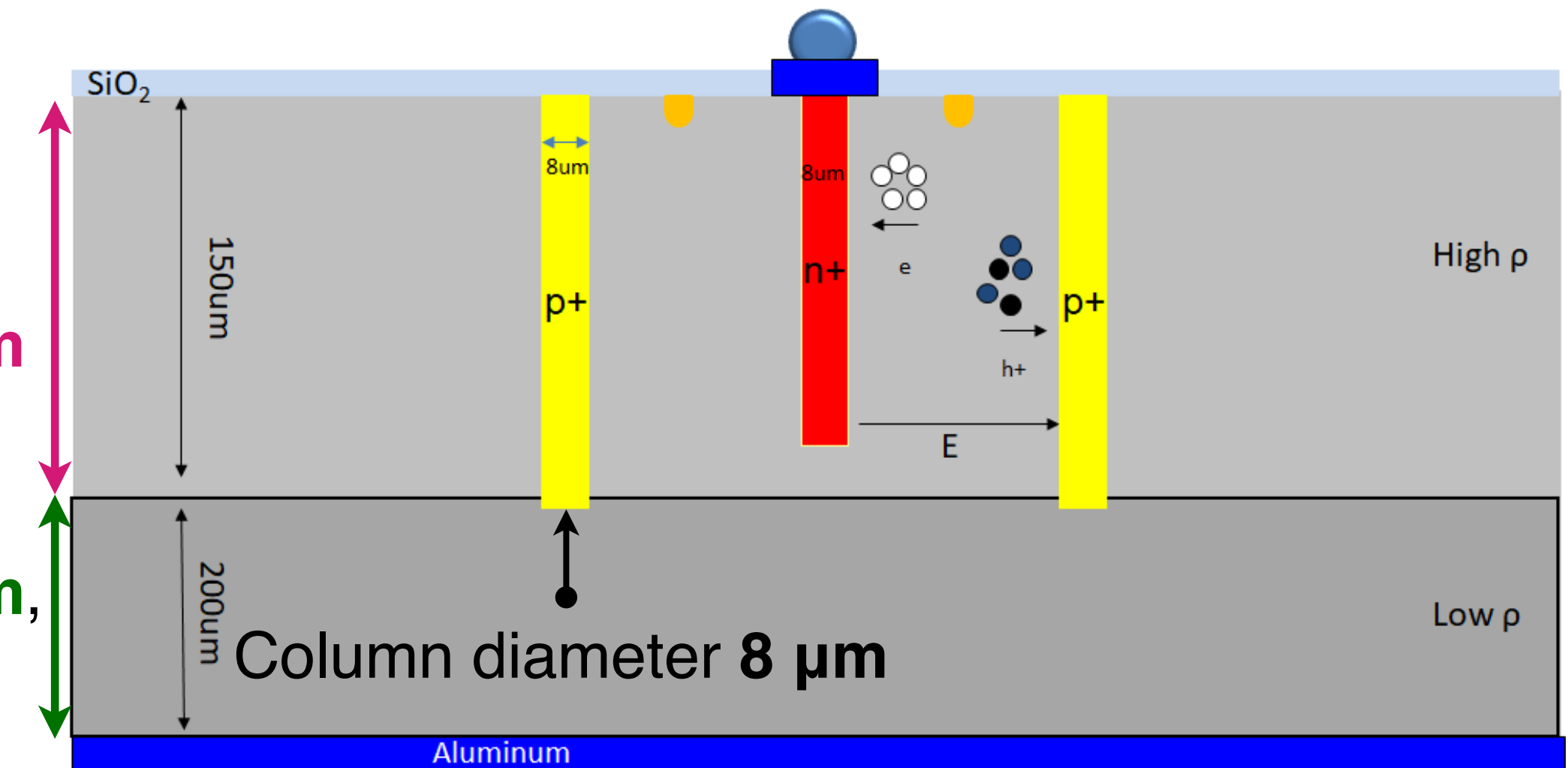
Next year we will choose the strategy for changing barrel layer 1 during HL-LHC era





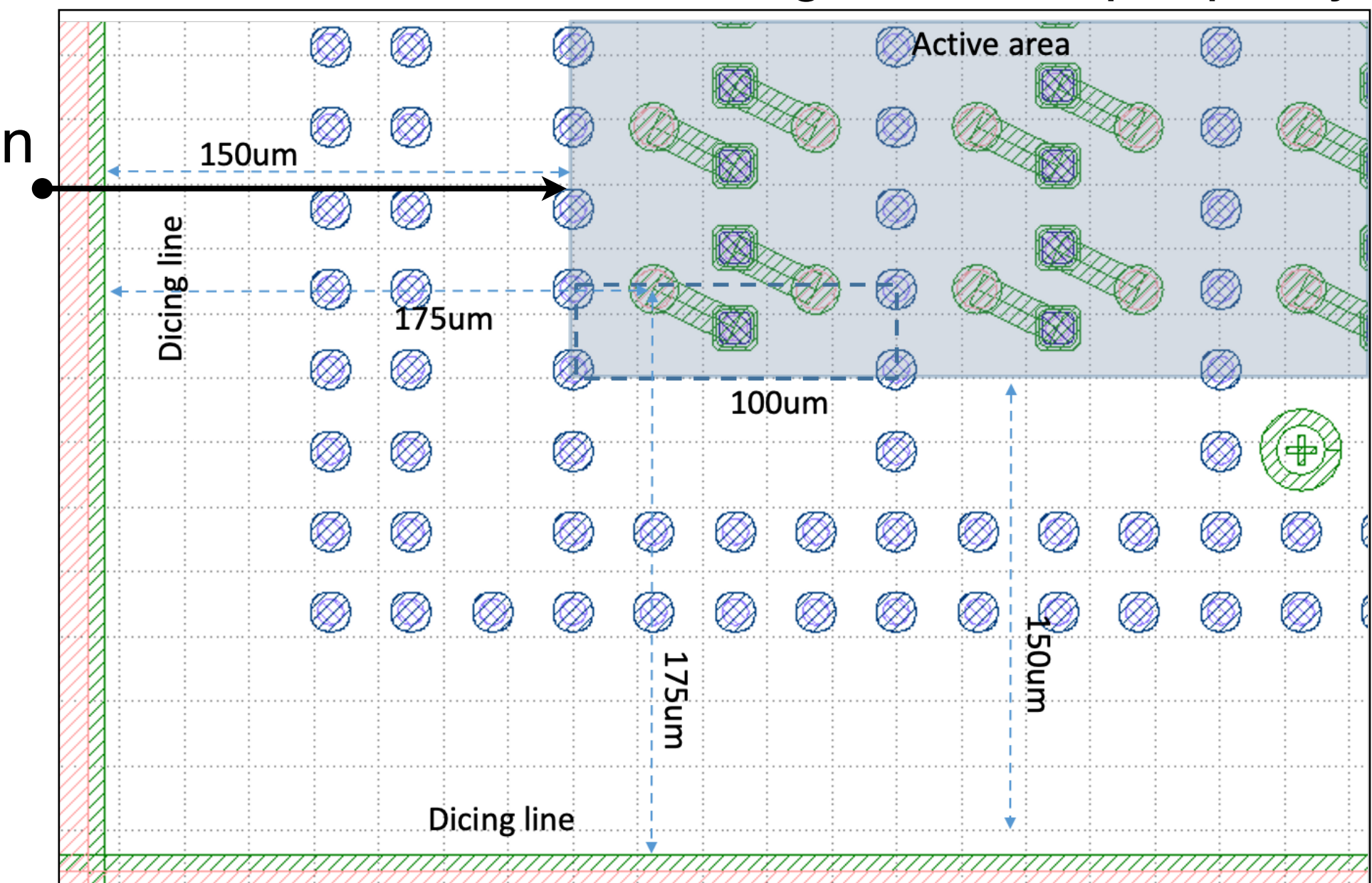
Active layer
thickness **150 μm**

Support wafer
thickness **200 μm** ,
after thinning
50-100 μm



- Pitch 25 x 100 μm^2
- 1E, one junction column electrode per pixel cell

Design mask of periphery

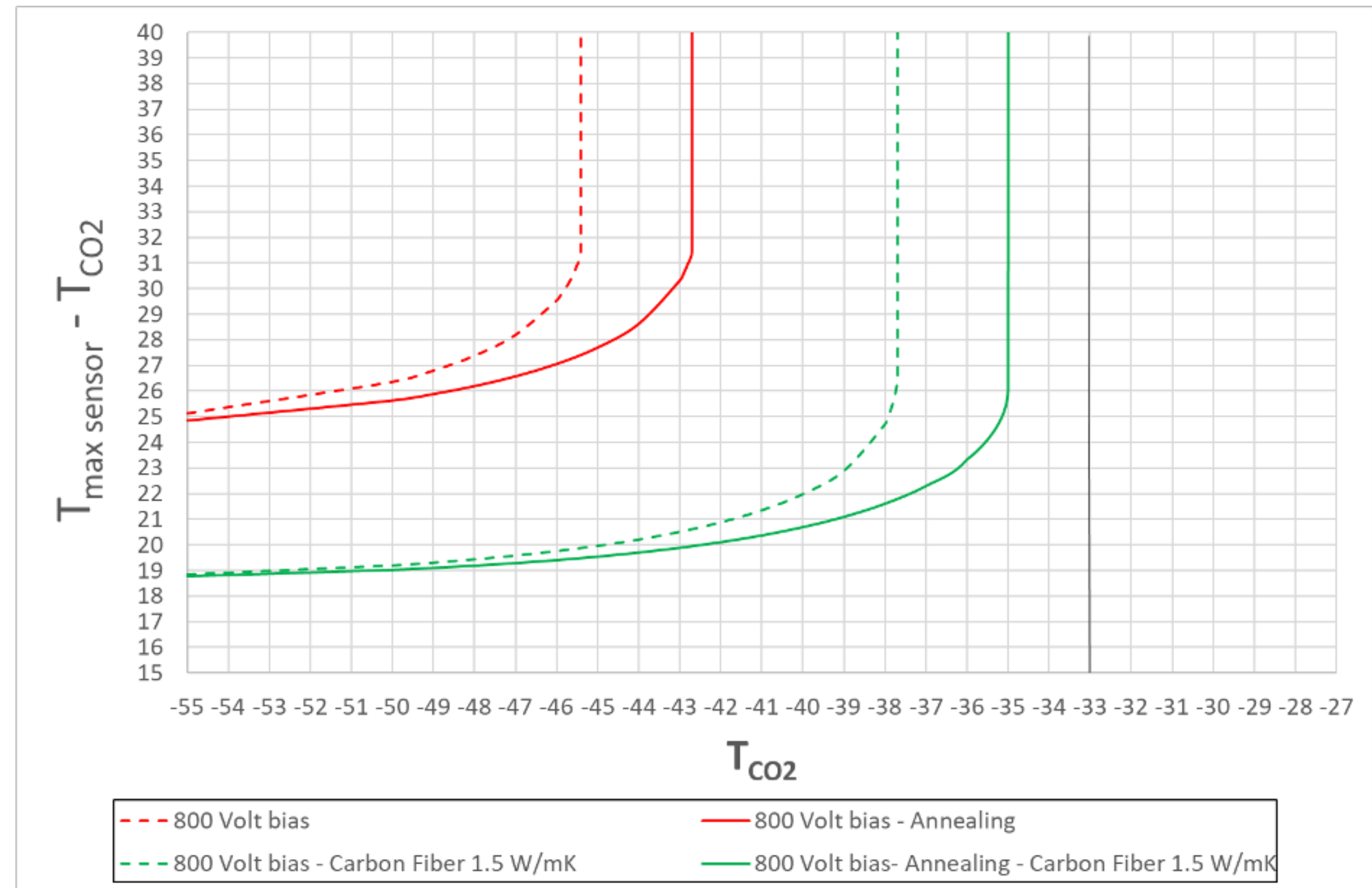
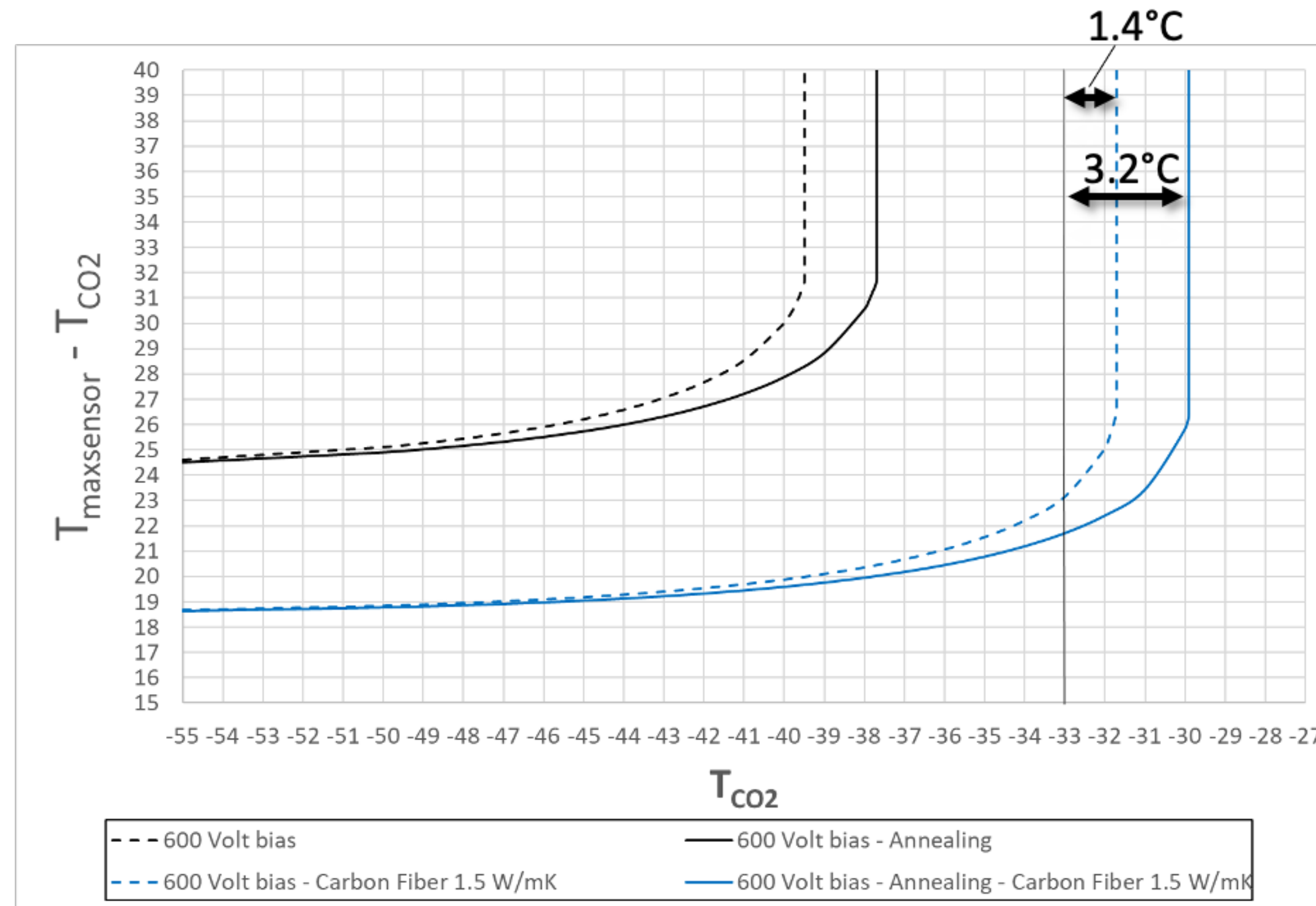


- a) Two wafers bonded with **DWB** technique as **FBK**
- b) **DRIE** to make holes on frontside for ohmic columns
- c) & d) deposit and filling with polysilicon
- e) & f) **DRIE** to make holes on frontside for junction columns and then polysilicon deposition
- g) & h) **metallisation**

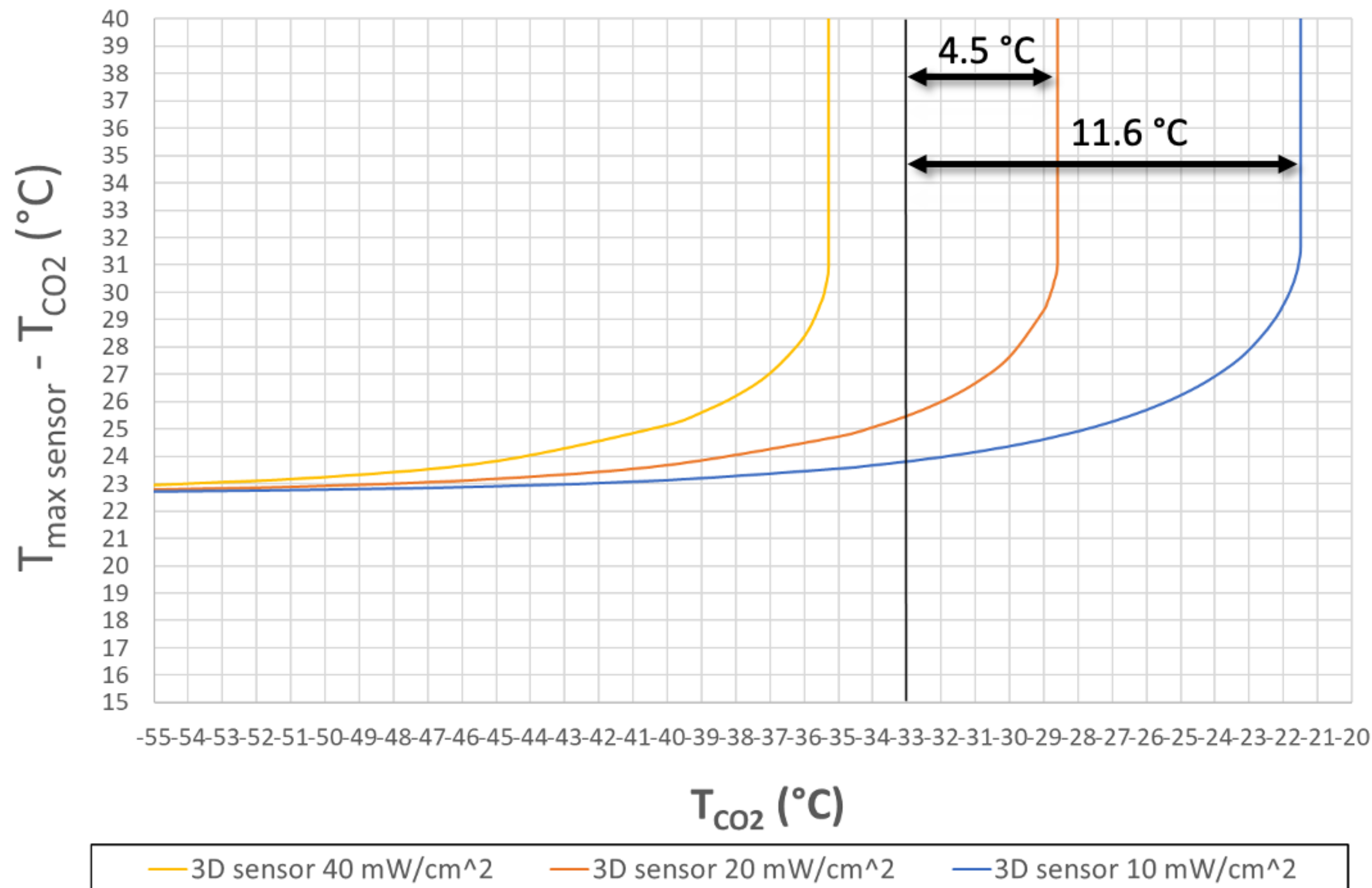
Planar sensor - barrel layer 1

Thermal conductivity (through plane) carbon fiber effect

Well cooled module



Thermal studies



3D sensor - barrel layer 1

Thermal conductivity (through plane)
carbon fiber effect

Main driving reason for choosing 3Ds for barrel layer 1

- Planar sensors at 1E16: 3°C margin at 600 V but thermal runaway at 800 V
- 3D sensors at 2E16: > 4.5°C margin at 150 V → large margin for 3D at 1E16

- **Corrywrekan framework for alignment and analysis:**
<https://project-corryvreckan.web.cern.ch/project-corryvreckan/>
- **Telescope EUDAQ-DAQ:** <https://eudaq.github.io>
- **RD53 Ph2_ACF-DAQ:** https://gitlab.cern.ch/cms_tk_ph2/Ph2_ACF